

RL78/L12

**RENESAS MCU** 

R01DS0157EJ0001 Rev.0.01 2012.02.20

Integrated LCD controller/driver, True Low Power Platform (as low as 75  $\mu$ A/MHz, and 0.64  $\mu$ A for RTC + LVD), 1.6 V to 5.5 V operation, 8 to 32 Kbyte Flash, 31 DMIPS at 24 MHz, for All LCD Based Applications

#### 1. OUTLINE

#### 1.1 Features

#### **Ultra-Low Power Technology**

- 1.6 V to 5.5 V operation from a single supply
- Stop (RAM retained): 0.23  $\mu$ A, (LVD enabled): 0.31  $\mu$ A
- Halt (RTC + LVD): 0.64 μA
- Supports snooze
- Operating: 75 μA/MHz
- LCD operating current (Capacitor split method): 0.12 μA
- LCD operating current (Internal voltage boost method): 1.0  $\mu$ A

#### 16-bit RL78 CPU Core

- Delivers 31 DMIPS at maximum operating frequency of 24 MHz
- Instruction Execution: 86% of instructions can be executed in 1 to 2 clock cycles
- CISC Architecture (Harvard) with 3-stage pipeline
- Multiply Signed & Unsigned: 16 x 16 to 32-bit result in 1 clock cycle
- MAC: 16 x 16 to 32-bit result in 2 clock cycles
- 16-bit barrel shifter for shift & rotate in 1 clock cycle
- 1-wire on-chip debug function

#### **Code Flash Memory**

- Density: 8 KB to 32 KB
- Block size: 1 KB
- On-chip single voltage flash memory with protection from block erase/writing
- Self-programming with secure boot swap function and flash shield window function

#### **Data Flash Memory**

- Data flash with background operation
- Data flash size: 2 KB size
- Erase cycles: 1 Million (typ.)
- Erase/programming voltage: 1.8 V to 5.5 V

#### RAM

- 1 KB and 1.5 KB size options
- Supports operands or instructions
- Back-up retention in all modes

#### **High-speed On-chip Oscillator**

- 24 MHz with +/- 1% accuracy over voltage (1.8 V to 5.5 V) and temperature (-20°C to 85°C) <target>
- Pre-configured settings: 24 MHz, 16 MHz, 12 MHz, 8 MHz, 4 MHz & 1 MHz

#### **Reset and Supply Management**

- Power-on reset (POR) monitor/generator
- Low voltage detection (LVD) with 14 setting options (Interrupt and/or reset function)

#### LCD Controller/Driver

- Up to 35 seg x 8 com or 39 seg x 4 com
- Supports capacitor split method, internal voltage boost method and resistance division method
- · Supports waveform types A and B
- Supports LCD contrast adjustment (18 steps)
- Supports LCD blinking

#### **Data Memory Access (DMA) Controller**

- Up to 2 fully programmable channels
- Transfer unit: 8- or 16-bit

#### **Multiple Communication Interfaces**

- Up to 1 × I<sup>2</sup>C multi-master
- Up to 2 × CSI/SPI (7-, 8-bit)
- Up to 1 × UART (7-, 8-, 9-bit)
- Up to 1 × LIN

#### **Extended-Function Timers**

- Multi-function 16-bit timers: Up to 8 channels
- Real-time clock (RTC): 1 channel (full calendar and alarm function with watch correction function)
- Interval Timer: 12-bit, 1 channel
- 15 kHz watchdog timer: 1 channel (window function)

#### **Rich Analog**

- ADC: Up to 10 channels, 10-bit resolution, 2.1  $\mu$ s conversion time
- Supports 1.6 V
- Internal voltage reference (1.45 V)
- On-chip temperature sensor

#### Safety Features (IEC or UL 60730 compliance)

- Flash memory CRC calculation
- · RAM parity error check
- RAM write protection
- SFR write protection
- Illegal memory access detection
- Clock frequency detection
- ADC self-test

#### General Purpose I/O

- 5V tolerant, high-current (up to 20 mA per pin)
- Open-Drain, Internal Pull-up support

#### **Operating Ambient Temperature**

• Standard: -40 °C to +85 °C

#### **Package Type and Pin Count**

From 7mm x 7mm to 12mm x 12mm QFP: 32, 44, 48, 52, 64 QFN: 64

#### O ROM, RAM capacities

Flash	Data	RAM			RL78/L12		
ROM	flash		32 pins	44 pins	48 pins	52 pins	64 pins
32 KB	2 KB	1.5 KB <sup>Note</sup>	R5F10RBC	R5F10RFC	R5F10RGC	R5F10RJC	R5F10RLC
16 KB	2 KB	1 KB <sup>Note</sup>	R5F10RBA	R5F10RFA	R5F10RGA	R5F10RJA	R5F10RLA
8KB	2 KB	1 KB <sup>Note</sup>	R5F10RB8	R5F10RF8	R5F10RG8	R5F10RJ8	-

**Note** In the case of the 1 KB, and 1.5 KB, this is 630 bytes when the self-programming function and data flash function is used.

Remark The functions mounted depend on the product. See 1.6 Outline of Functions.

# 1.2 Ordering Information

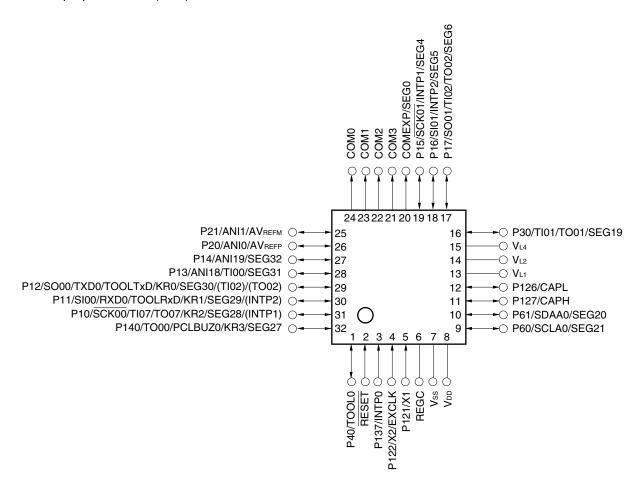
#### • Flash memory version (lead-free product)

Pin count	Package	Part Number
32 pins	32-pin plastic LQFP (7 × 7)	R5F10RB8AFP, R5F10RBAAFP, R5F10RBCAFP
44 pins	44-pin plastic LQFP (10 × 10)	R5F10RF8AFP, R5F10RFAAFP, R5F10RFCAFP
48 pins	48-pin plastic LQFP (fine pitch) (7 × 7)	R5F10RG8AFB, R5F10RGAAFB, R5F10RGCAFB
52 pins	52-pin plastic LQFP (10 × 10)	R5F10RJ8AFA, R5F10RJAAFA, R5F10RJCAFA
64 pins	64-pin plastic WQFN (8 × 8)	R5F10RLAANB, R5F10RLCANB
	64-pin plastic LQFP (fine pitch) (10 × 10)	R5F10RLAAFB, R5F10RLCAFB
	4-pin plastic LQFP (12 × 12)	R5F10RLAAFA, R5F10RLCAFA

#### 1.3 Pin Configuration (Top View)

#### 1.3.1 32-pin products

• 32-pin plastic LQFP (7 × 7)

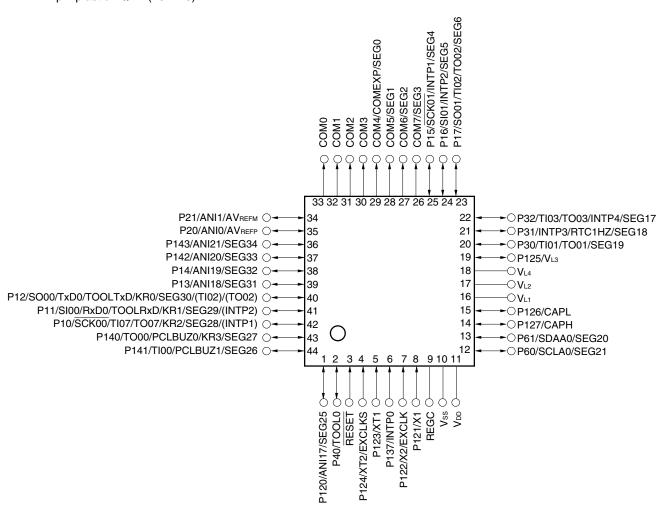


Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F).

- Remarks 1. For pin identification, see 1.4 Pin Identification.
  - 2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR)

#### 1.3.2 44-pin products

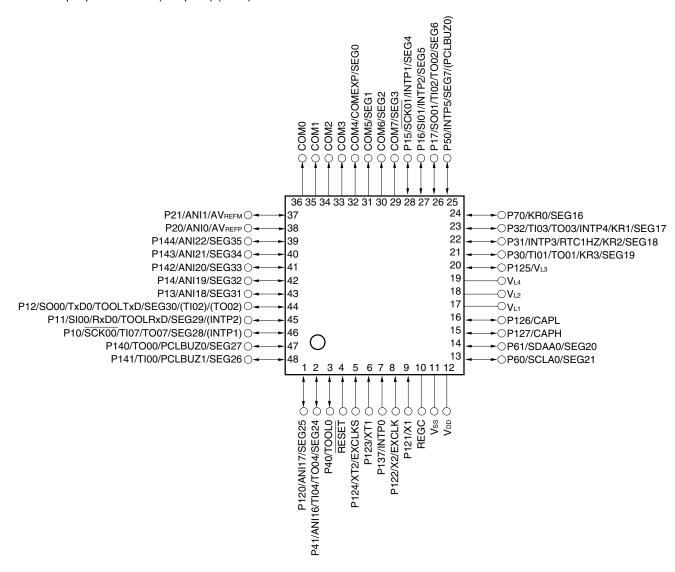
• 44-pin plastic LQFP (10 × 10)



Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F).

- Remarks 1. For pin identification, see 1.4 Pin Identification.
  - 2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR)

• 48-pin plastic LQFP (fine pitch) (7 × 7)



Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F).

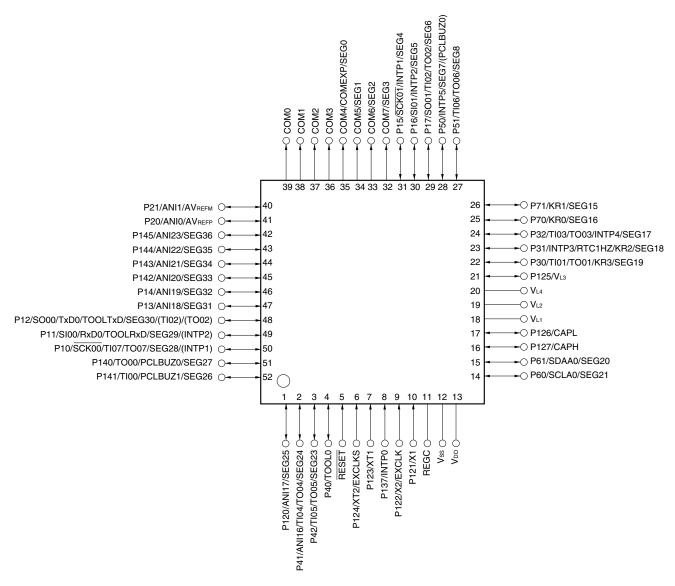
Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR)

Specifications in this document are tentative and subject to change.

#### 1.3.4 52-pin products

• 52-pin plastic LQFP (10 × 10)

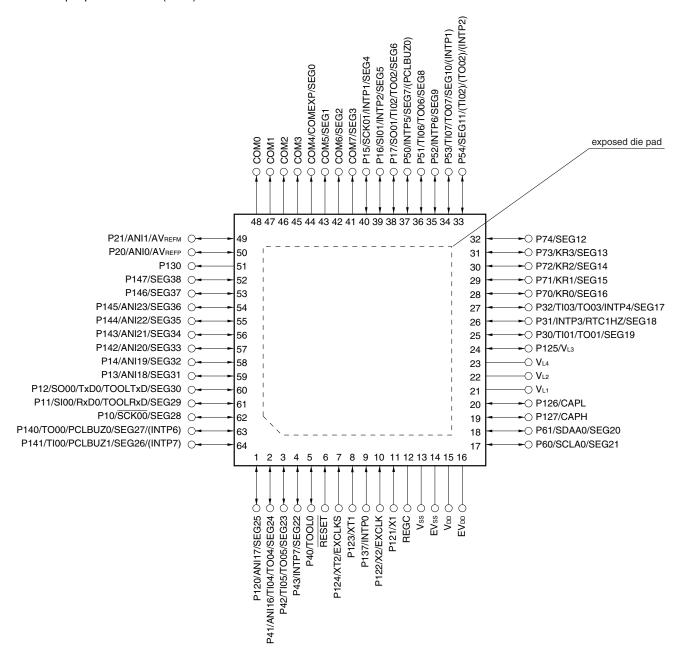


Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F).

- Remarks 1. For pin identification, see 1.4 Pin Identification.
  - 2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR)

# 1.3.5 64-pin products

• 64-pin plastic WQFN (8 × 8)

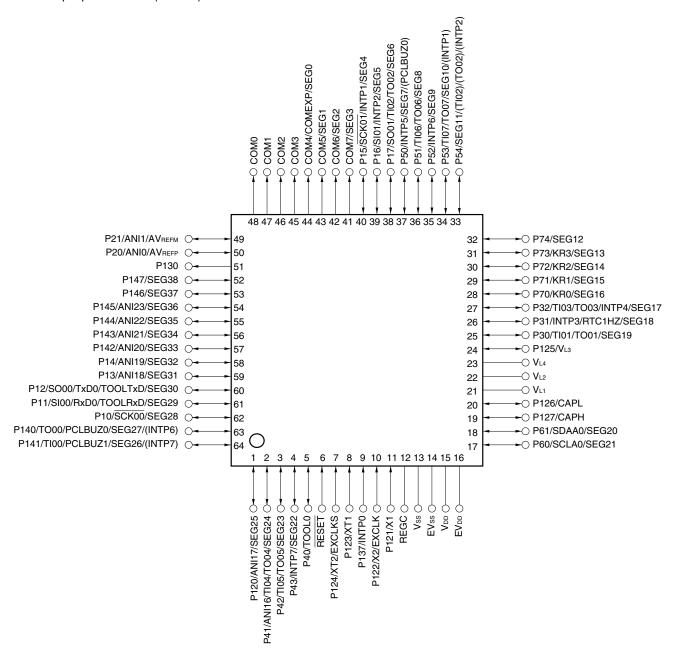


- Cautions 1. Make EVss pin the same potential as Vss pin.
  - 2. Make VDD pin the potential that is higher than EVDD pin.
  - 3. Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F).

#### Remarks 1. For pin identification, see 1.4 Pin Identification.

- 2. When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the V<sub>DD</sub> and EV<sub>DD</sub> pins and connect the Vss and EVss pins to separate ground lines.
- **3.** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR)

- 64-pin plastic LQFP (fine pitch) (10 × 10)
- 64-pin plastic LQFP (12 × 12)



- Cautions 1. Make EVss pin the same potential as Vss pin.
  - 2. Make VDD pin the potential that is higher than EVDD pin.
  - 3. Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F).
- Remarks 1. For pin identification, see 1.4 Pin Identification.
  - 2. When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the  $V_{\text{DD}}$  and EV<sub>DD</sub> pins and connect the Vss and EVss pins to separate ground lines.
  - 3. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR)

RL78/L12 1. OUTLINE

#### 1.4 Pin Identification

ANI0, ANI1,		P120 to P127:	Port 12
ANI16 to ANI23:	Analog Input	P130, P137:	Port 13
AVREFM:	Analog Reference	P140 to P147:	Port 14
	Voltage Minus	PCLBUZ0, PCLBUZ1:	Programmable Clock
AVREFP:	Analog Reference		Output/Buzzer Output
	Voltage Plus	REGC:	Regulator Capacitance
CAPH, CAPL:	Capacitor for LCD	RESET:	Reset
COM0 to COM7,		RTC1HZ:	Real-time Clock Correction Clock
COMEXP:	LCD Common Output		(1 Hz) Output
EV <sub>DD</sub> :	Power Supply for Port	RxD0:	Receive Data
EVss:	Ground for Port	SCK00, SCK01:	Serial Clock Input/Output
EXCLK:	External Clock Input	SCLA0:	Serial Clock Input/Output
	(Main System Clock)	SDAA0:	Serial Data Input/Output
EXCLKS:	External Clock Input	SEG0 to SEG38:	LCD Segment Output
	(Sub System Clock)	SI00, SI01:	Serial Data Input
INTP0 to INTP7:	External Interrupt Input	SO00, SO01:	Serial Data Output
KR0-KR3:	Key Return	TI00 to TI07:	Timer Input
P10 to P17:	Port 1	TO00 to TO07:	Timer Output
P20, P21:	Port 2	TOOL0:	Data Input/Output for Tool
P30 to P32:	Port 3	TOOLRxD, TOOLTxD:	Data Input/Output for External Device
P40 to P43:	Port 4	TxD0:	Transmit Data
P50 to P54:	Port 5	V <sub>DD</sub> :	Power Supply
P60, P61:	Port 6	VL1 to VL4:	LCD Power Supply
P70 to P74:	Port 7	Vss:	Ground

X1, X2:

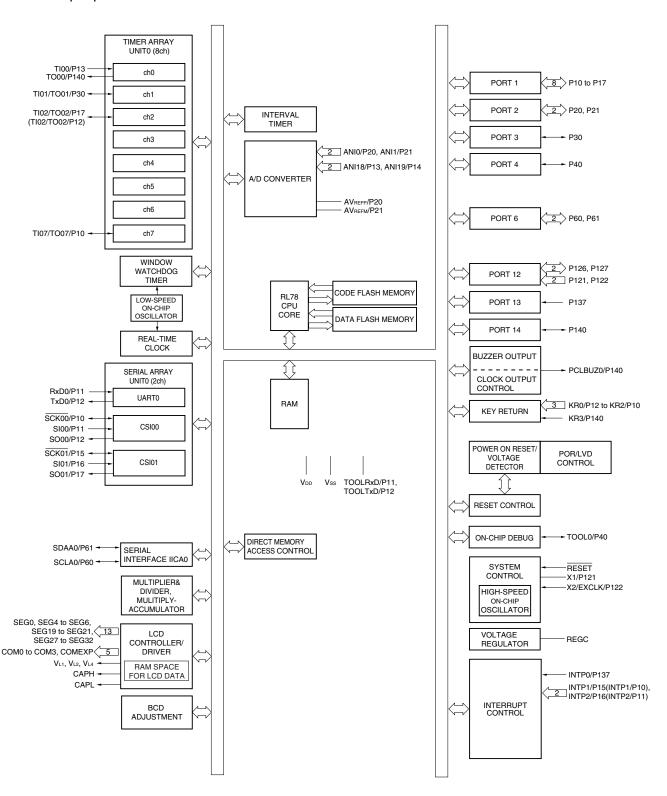
XT1, XT2:

Crystal Oscillator (Main System Clock)

Crystal Oscillator (Subsystem Clock)

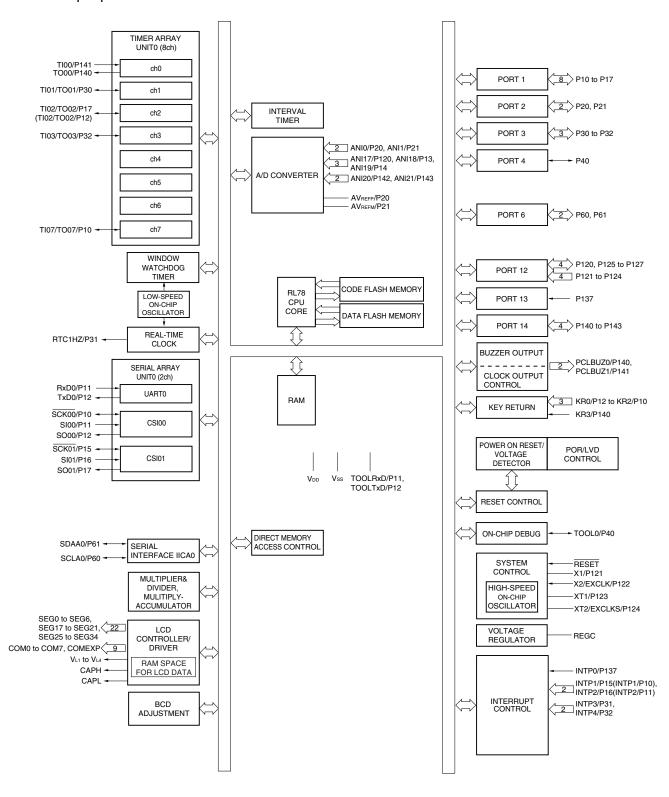
#### 1.5 Block Diagram

#### 1.5.1 32-pin products



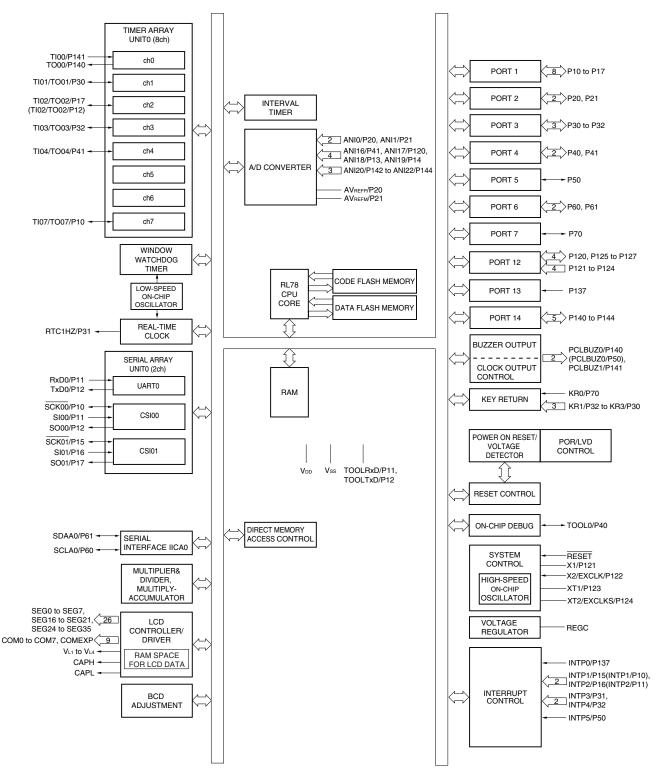
**Remark** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR)

#### 1.5.2 44-pin products



**Remark** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR)

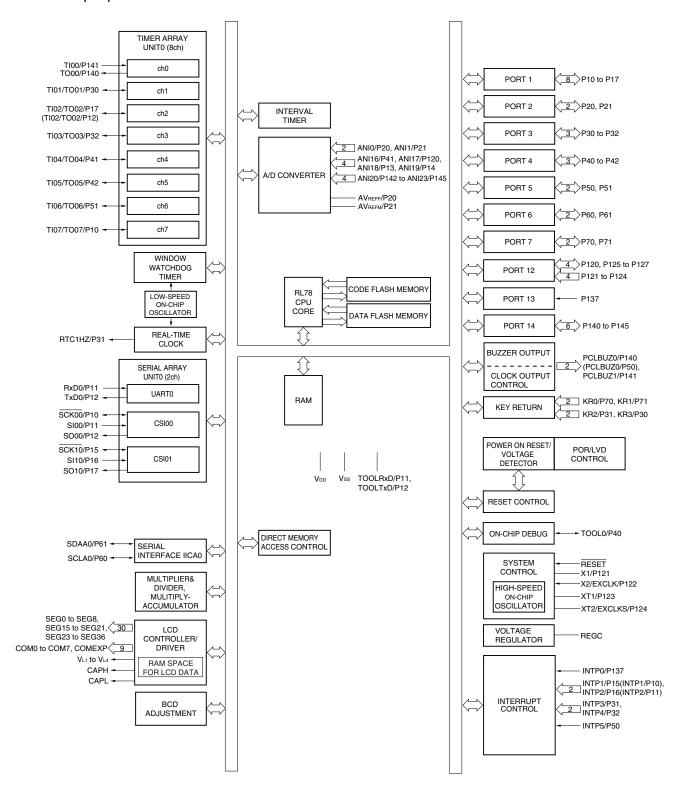
#### 1.5.3 48-pin products



**Remark** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR)

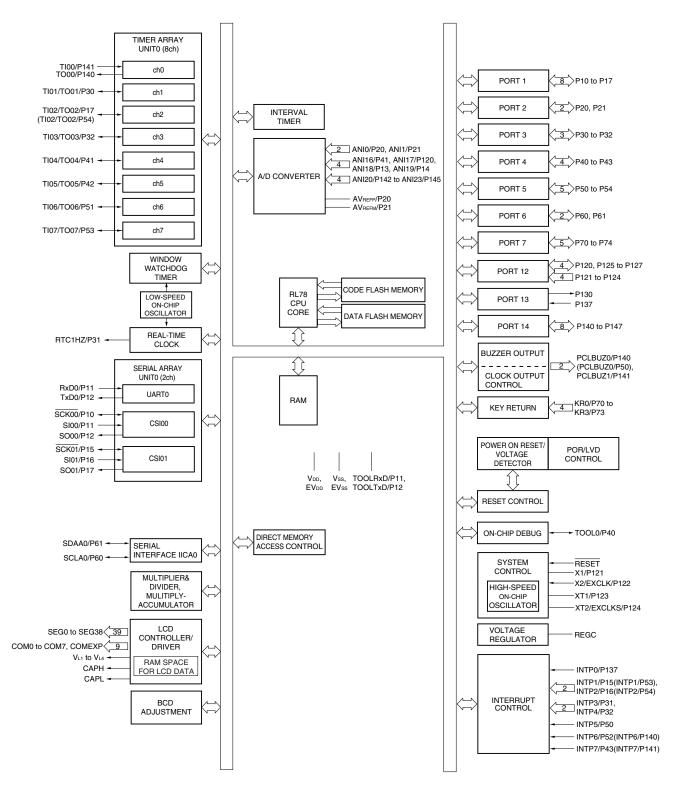
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#### 1.5.4 52-pin products



**Remark** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR)

#### 1.5.5 64-pin products



**Remark** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR)

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#### 1.6 Outline of Functions

# Caution This outline describes the functions at the time when Peripheral I/O redirection register (PIOR) is set to 00H.

(1/2)

					(1/2)		
Item	32-pin	44-pin	48-pin	52-pin	64-pin		
	R5F10RBx	R5F10RFx	R5F10RGx	R5F10RJx	R5F10RLx		
Code flash memory (KB)		8 to 32	8 to 32	8 to 32	16, 32		
Data flash memory (KB)		2	2	2	2		
	1, 1.5 Note 1	1, 1.5 Note 1	1, 1.5 Note 1	1, 1.5 Note 1	1, 1.5 <sup>Note 1</sup>		
e	1 MB						
High-speed system clock		X1 (crystal/ceramic) oscillation, external main system clock input (EXCLK) 1 to 20 MHz: $V_{DD} = 2.7$ to 5.5 V, 1 to 8 MHz: $V_{DD} = 1.8$ to 2.7 V, 1 to 4 MHz: $V_{DD} = 1.6$ to 1.8 V					
High-speed on-chip oscillator clock	to 16 MHz (VDD	= 2.4 to 5.5 V), L	_ow-speed opera	ition: 1 to 8 MHz			
lock	_	` , ,	•	•	input (EXCLKS)		
n-chip oscillator clock			V				
ose register	8 bits × 32 registers (8 bits × 8 registers × 4 banks)						
ruction execution time	0.04167 $\mu$ s (High-speed on-chip oscillator clock: f <sub>IH</sub> = 24 MHz operation)						
	0.05 μs (High-speed system clock: f <sub>MX</sub> = 20 MHz operation)						
	30.5 $\mu$ s (Subsystem clock: fsub = 32.768 kHz operation)						
st.	<ul><li>Adder and s</li><li>Multiplication</li></ul>	ubtractor/logical n (8 bits × 8 bits)			Boolean		
Total	20	29	33	37	47		
CMOS I/O	15	22	26	30	39		
CMOS input	3	5	5	5	5		
CMOS output	-	-	_	-	1		
N-ch open-drain I/O (6 V tolerance)	2	2	2	2	2		
16-bit timer	8 channels	8 channels	(with 1 channel r	emote control ou	itput function)		
Watchdog timer			1 channel				
Real-time clock (RTC)			1 channel				
Interval timer (IT)			1 channel				
Timer output	4 channels	5 channels (PWM outputs:	6 channels (PWM outputs:	8 channels (PWM outputs: 7 Note 2			
·	(PWM outputs: 3 Note 2)	$4^{\text{Note }2}$ )	5 Note 2)				
	emory (KB)  emory (KB)  emory (KB)  High-speed system clock  High-speed on-chip oscillator clock  ock  n-chip oscillator clock  ose register  ruction execution time  t  Total  CMOS I/O  CMOS input  CMOS output  N-ch open-drain I/O  (6 V tolerance)  16-bit timer  Watchdog timer  Real-time clock (RTC)	emory (KB)  emory (KB)  emory (KB)  2  1, 1.5 Note 1  te	R5F10RBx   R5F10RFx	R5F10RBx   R5F10RFx   R5F10RGx	## R5F10RBX   R5F10RFX   R5F10RGX   R5F10RJX   ## R5F10RBX   R5F10RGX   R5F10RJX   ## R5F10RBX   R5F10RGX   R5F10RJX   ## R5F10RBX   R5F10RGX   R5F10RJX   ## R5F10RJX   R5F10RJ		

**Notes 1.** In the case of the 1 KB, and 1.5 KB, this is 630 bytes when the self-programming function and data flash function is used.

2. The number of outputs varies, depending on the setting.

(2/2)

						(2/2)	
Ite	m	32-pin	44-pin	48-pin	52-pin	64-pin	
		R5F10RBx	R5F10RFx	R5F10RGx	R5F10RJx	R5F10RLx	
Clock output/buzz	er output	1			2		
		(Main system	<ul> <li>2.44 kHz, 4.88 kHz, 9.76 kHz, 1.25 MHz, 2.5 MHz, 5 MHz, 10 MHz (Main system clock: fmain = 20 MHz operation)</li> <li>256 Hz, 512 Hz, 1.024 kHz, 2.048 kHz, 4.096 kHz, 8.192 kHz, 16.384 kHz,</li> </ul>				
		32.768 kHz	clock: fsuB = 32.70	·		,	
8/10-bit resolution	A/D converter	4 channels	7 channels	9 channels	10 channels	10 channels	
Serial interface		CSI: 2 chan	nel/UART (LIN-bi	us supported): 1	channel		
I <sup>2</sup> C bus		1 channel	1 channel	1 channel	1 channel	1 channel	
LCD controller/driv	ver .	Internal voltage division method are swi	boosting method	d, capacitor split	method, and exte	ernal resistance	
Segment sig	gnal output	13	22 (18) Note 1	26 (22) Note 1	30 (26) Note 1	39 (35) Note 1	
Common sig		4	Note 1				
Multiplier and divider/multiply-ac	Multiplier and divider/multiply-accumulator		<ul> <li>16 bits × 16 bits = 32 bits (Unsigned or signed)</li> <li>32 bits ÷ 32 bits = 32 bits (Unsigned)</li> <li>16 bits × 16 bits + 32 bits = 32 bits (Unsigned or signed)</li> </ul>				
DMA controller		2 channels					
Vectored interrupt	Internal	23	23	23	23	23	
sources	External	4	6	7	7	9	
Key interrupt				4			
Reset		<ul> <li>Reset by RESET pin</li> <li>Internal reset by watchdog timer</li> <li>Internal reset by power-on-reset</li> <li>Internal reset by voltage detector</li> <li>Internal reset by illegal instruction execution Note 2</li> <li>Internal reset by RAM parity error</li> <li>Internal reset by illegal-memory access</li> </ul>					
Power-on-reset circuit		Power-on-reset: 1.51 ±0.03 V     Power-down-reset: 1.50 ±0.03 V					
Voltage detector		1.63 V to 4.06 \	/ (14 stages)				
On-chip debug fur	nction	Provided					
Power supply volta	age	V <sub>DD</sub> = 1.6 to 5.5	5 V				
Operating ambien	t temperature	T <sub>A</sub> = -40 to +85	5°C				

**Notes 1.** The values in parentheses are the number of signal outputs when 8 com is used.

2. The illegal instruction is generated when instruction code FFH is executed. Reset by the illegal instruction execution not issued by emulation with the in-circuit emulator or on-chip debug emulator.

#### 2. **ELECTRICAL SPECIFICATIONS (TARGET)**

- Cautions 1. These specifications show target values, which may change after device evaluation.
  - 2. The RL78/L12 have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
  - 3. The pins mounted depend on the product. Refer to 1.3.1 32-pin products to 1.3.5 64-pin products.

#### 2.1 Absolute Maximum Ratings

#### Absolute Maximum Ratings ( $T_A = 25^{\circ}C$ ) (1/3)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	V <sub>DD</sub>	$V_{DD} = EV_{DD}$	-0.5 to +6.5	V
	EV <sub>DD</sub>	$V_{DD} = EV_{DD}$	-0.5 to +6.5	٧
	Vss		-0.5 to +0.3	٧
	EVss		-0.5 to +0.3	V
REGC pin input voltage	VIREGC	REGC	$-0.3 \text{ to } +2.8$ and $-0.3 \text{ to V}_{DD} +0.3^{\text{Note 1}}$	V
Input voltage	VII	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	$-0.3$ to EV <sub>DD</sub> +0.3 and -0.3 to V <sub>DD</sub> +0.3 $^{\text{Note 2}}$	V
	V <sub>12</sub>	P60, P61 (N-ch open-drain)	-0.3 to +6.5	V
	Vıз	P20, P21, P121 to P124, P137, EXCLK, EXCLKS, RESET	-0.3 to V <sub>DD</sub> +0.3 <sup>Note 2</sup>	V
Output voltage	Vo <sub>1</sub>	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P130, P140 to P147	-0.3 to EV <sub>DD</sub> +0.3 and -0.3 to V <sub>DD</sub> +0.3 <sup>Note 2</sup>	V
	V <sub>02</sub>	P20, P21	-0.3 to V <sub>DD</sub> +0.3	V
Analog input voltage	VAI1	ANI16 to ANI23	-0.3 to EV <sub>DD</sub> +0.3 and $-0.3$ to AV <sub>REFP</sub> +0.3 <sup>Note 2</sup>	V
	V <sub>Al2</sub>	ANIO, ANI1	$-0.3$ to V <sub>DD</sub> +0.3 and $-0.3$ to AV <sub>REFP</sub> +0.3 $^{\text{Note 2}}$	V

- Notes 1. Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.
  - 2. Must be 6.5 V or lower.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



#### Absolute Maximum Ratings (TA = 25°C) (2/3)

Parameter	Symbols		Conditions		Ratings	Unit
LCD voltage	V <sub>LI1</sub>	V <sub>∟1</sub> input voltage	Note 1		-0.3 to +V <sub>LI2</sub>	V
	V <sub>LI2</sub>	VL2 input voltage <sup>Note 1</sup>			VLI1 to VLI3 Note 2	V
	VLI3	V <sub>L3</sub> input voltage	Note 1		VLI2 to VLI4	٧
	V <sub>LI4</sub>	V <sub>L4</sub> input voltage	Note 1		V <sub>LI3</sub> <sup>Note 3</sup> to +6.5	V
	V <sub>LI5</sub>	CAPL, CAPH inp	ut voltage <sup>Note 1</sup>		-0.3 to +6.5	V
	V <sub>LO1</sub>	V <sub>∟1</sub> output voltage	е		-0.3 to +VLO2	٧
	V <sub>LO2</sub>	VL2 output voltage	e		VLO1 to VLO3 Note 4	V
	<b>V</b> LO3	V∟₃ output voltage	e		VLO2 to VLO4	٧
	V <sub>LO4</sub>	V <sub>L4</sub> output voltage			VL03 <sup>Note 5</sup> to +6.5	٧
	V <sub>LO5</sub>	CAPL, CAPH output voltage			-0.3 to +6.5	V
	VLO6	COM0 to COM7, SEG0 to SEG38, COMEXP output voltage		When other than a memory-type liquid crystal waveform is used	-0.3 to V <sub>DD</sub> +0.3 <sup>Note 6</sup>	V
				When a memory-type liquid crystal waveform is used	-0.3 to V <sub>LI4</sub> +0.3 <sup>Note 6</sup>	V
			Capacitor split m	ethod	-0.3 to V <sub>DD</sub> +0.3 <sup>Note 6</sup>	V
			Internal voltage b	poosting method	-0.3 to V <sub>LI4</sub> +0.3 <sup>Note 6</sup>	V

- Notes 1. This value only indicates the absolute maximum ratings when applying voltage to the V<sub>L1</sub>, V<sub>L2</sub>, V<sub>L3</sub>, and V<sub>L4</sub> pins; it does not mean that applying voltage to these pins is recommended. When using the internal voltage boosting method or capacitance split method, connect these pins to Vss via a capacitor (0.47  $\mu$  F  $\pm$  30%) and connect a capacitor (0.47  $\mu$  F  $\pm$  30%) between the CAPL and CAPH pins.
  - **2.** This is  $V_{L14}$  in 32-pin products or when the 1/3 bias method is used.
  - 3. This is V<sub>LI2</sub> in 32-pin products or when the 1/3 bias method is used. It is V<sub>LI1</sub> when the 1/2 bias method is used. It is -0.3 in static mode.
  - **4.** This is  $V_{LO4}$  in 32-pin products or when the 1/3 bias method is used.
  - 5. This is V<sub>LO2</sub> in 32-pin products or when the 1/3 bias method is used. It is V<sub>LO1</sub> when the 1/2 bias method is used. It is -0.3 in static mode.
  - 6. Must be 6.5 V or lower.

#### **ELECTRICAL SPECIFICATIONS (TARGET)**

Caution The pins mounted depend on the product. Refer to 1.3.1 32-pin products to 1.3.5 64-pin products.

Absolute Maximum Ratings (TA = 25°C) (3/3)

Parameter	Symbols		Conditions	Ratings	Unit
Output current, high	Іон1	Per pin	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P130, P140 to P147	-40	mA
		Total of all pins -170 mA	P10 to P14, P40 to P43, P120, P130, P140 to P147	-70	mA
			P15 to P17, P30 to P32, P50 to P54, P70 to P74, P125-P127	-100	mA
	10н2	Per pin	P20, P21	-0.5	mA
		Total of all pins		-1	mA
Output current, low	lo <sub>L1</sub>	Per pin	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P130, P140 to P147	40	mA
		Total of all pins 170 mA	P10 to P14, P40 to P43, P120, P130, P140 to P147	70	mA
			P15 to P17, P30 to P32, P50 to P54, P60, P61, P70 to P74, P125 to P127	100	mA
	lo <sub>L2</sub>	Per pin	P20, P21	1	mA
		Total of all pins	]	2	mA
Operating ambient	Та	In normal operati	on mode	-40 to +85	°C
temperature		In flash memory	In flash memory programming mode		
Storage temperature	Tstg			-65 to +150	°C

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

#### 2.2 Oscillator Characteristics

#### 2.2.1 Main system clock oscillator characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Resonator	Recommended Circuit	Parameter	Conditions	MIN.	TYP.	MAX.	Unit
Ceramic resonator	V <sub>00</sub> V1 V2	X1 clock oscillation	$2.7~V \leq V_{DD} \leq 5.5~V$	1.0		20.0	MHz
	Vss X1 X2	frequency (fx) <sup>Note</sup>	$1.8~V \leq V_{\text{DD}} < 2.7~V$	1.0		8.0	MHz
	C1= C2=		$1.6~V \le V_{DD} < 1.8~V$	1.0		4.0	MHz
Crystal resonator		X1 clock oscillation	$2.7~V \leq V_{DD} \leq 5.5~V$	1.0		20.0	MHz
	Vss X1 X2	frequency (fx) <sup>Note</sup>	$1.8~V \leq V_{DD} < 2.7~V$	1.0		8.0	MHz
	C1= C2=		1.6 V ≤ V <sub>DD</sub> <1.8 V	1.0		4.0	MHz

Note Indicates only oscillator characteristics. Refer to AC Characteristics for instruction execution time.

Cautions 1. When using the X1 oscillator, wire as follows in the area enclosed by the broken lines in the above figures to avoid an adverse effect from wiring capacitance.

- . Keep the wiring length as short as possible.
- . Do not cross the wiring with the other signal lines.
- Do not route the wiring near a signal line through which a high fluctuating current flows.
- Always make the ground point of the oscillator capacitor the same potential as Vss.
- Do not ground the capacitor to a ground pattern through which a high current flows.
- Do not fetch signals from the oscillator.
- 2. Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

#### 2.2.2 On-chip oscillator characteristics

#### (Ta = -20 to +85°C, 1.6 V $\leq$ EVDD = VDD $\leq$ 5.5 V, Vss = EVss = 0 V)

Oscillators	Parameters	Conditions			TYP.	MAX.	Unit
High-speed	fін	$1.8~V \leq V_{\text{DD}} < 5.5~V$	24 MHz selected	23.76	24.00	24.24	MHz
on-chip oscillator			16 MHz selected	15.84	16.00	16.16	MHz
clock frequency		$1.6~V \leq V_{DD} < 1.8~V$	24 MHz selected	22.80	24.00	25.20	MHz
			16 MHz selected	11.40	16.00	16.80	MHz

**Note** This only indicates the oscillator characteristics. Refer to AC Characteristics for instruction execution time.

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$

Oscillators	Parameters	Conditions		MIN.	TYP.	MAX.	Unit
High-speed	fін	$1.8~V \leq V_{DD} < 5.5~V$	24 MHz selected	23.64	24.00	24.36	MHz
on-chip oscillator			16 MHz selected	15.76	16.00	16.24	MHz
clock frequency		$1.6~V \leq V_{DD} < 1.8~V$	24 MHz selected	22.68	24.00	25.32	MHz
			16 MHz selected	15.12	16.00	16.88	MHz

**Note** This only indicates the oscillator characteristics. Refer to AC Characteristics for instruction execution time.

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$

Oscillators	Parameters	Conditions	MIN.	TYP.	MAX.	Unit
Low-speed on-chip	fıL		12.75	15	17.25	kHz
oscillator clock						
frequency						

#### 2.2.3 Subsystem clock oscillator characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Resonator	Recommended Circuit	Items	Conditions	MIN.	TYP.	MAX.	Unit
Crystal resonator	Vss XT2 XT1  Rd  C4 — C3 —	XT1 clock oscillation frequency (fxt) <sup>Note</sup>		32	32.768	35	kHz

Note Indicates only oscillator characteristics. Refer to AC Characteristics for instruction execution time.

Cautions 1. When using the XT1 oscillator, wire as follows in the area enclosed by the broken lines in the above figures to avoid an adverse effect from wiring capacitance.

- . Keep the wiring length as short as possible.
- Do not cross the wiring with the other signal lines.
- Do not route the wiring near a signal line through which a high fluctuating current flows.
- Always make the ground point of the oscillator capacitor the same potential as Vss.
- Do not ground the capacitor to a ground pattern through which a high current flows.
- Do not fetch signals from the oscillator.
- 2. The XT1 oscillator is designed as a low-amplitude circuit for reducing power consumption, and is more prone to malfunction due to noise than the X1 oscillator. Particular care is therefore required with the wiring method when the XT1 clock is used.

Remark For the resonator selection and oscillator constant, customers are requested to either evaluate the oscillation themselves or apply to the resonator manufacturer for evaluation.



#### 2.3 DC Characteristics

#### 2.3.1 Pin characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}. \ 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}. \text{ Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Items	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
Output current, high <sup>Note 1</sup>	Іон1	·	110 to P17, P30 to P32, P40 t P120, P125 to P127, P130, F	· ·			-10.0 Note 3	mA
		Total of P10	to P14, P40 to P43, P120,	$4.0~V \leq EV_{DD} \leq 5.5~V$			-40.0	mA
			to P147	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}$			-8.0	mA
		(When duty	= 70% )	1.8 V ≤ EV <sub>DD</sub> < 2.7 V			-4.0	mA
				1.6 V ≤ EV <sub>DD</sub> < 1.8 V			-2.0	mA
		Total of P15	to P17, P30 to P32,	$4.0~V \leq EV_{DD} \leq 5.5~V$			-60.0	mA
		· · · · · · · · · · · · · · · · · · ·	P70 to P74, P125 to P127	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}$			-15.0	mA
		(When duty	= 70% )	1.8 V ≤ EV <sub>DD</sub> < 2.7 V			-8.0	mA
				1.6 V ≤ EV <sub>DD</sub> < 1.8 V			-4.0	mA
		Total of all p					-100.0	mA
	<b>І</b> он2	P20, P21	Per pin				-0.1 Note 3	mA
			Total of all pins (When duty = 70% Note 2)	$1.6~V \leq V_{DD} \leq 5.5~V$			-1.5	mA

- Notes 1. Value of current at which the device operation is guaranteed even if the current flows from the EVDD pin to an output pin.
  - 2. Specification under conditions where the duty factor is 70%.

The output current value that has changed the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins =  $(loh \times 0.7)/(n \times 0.01)$ 
  - <Example> Where n = 50% and IoH = -10.0 mA

Total output current of pins =  $(-10.0 \times 0.7)/(50 \times 0.01) = -14.0$  mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

3. Do not exceed the total current value.

Caution P10, P12, P15, P17 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Items	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
Output current, low Note 1	lol1	•	P10 to P17, P30 to P32, F 1, P70 to P74, P120, P125 147			20.0 Note 3	mA	
		Per pin for	P60, P61			15.0 Note 3	mA	
		Total of P1	0 to P14, P40 to P43,	$4.0~V \leq EV_{DD} \leq 5.5~V$			70.0	mA
		*	0, P140 to P147	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}$			15.0	mA
		(when dut	$y = 70\%^{\text{Note 2}})$	$1.8 \text{ V} \leq \text{EV}_{\text{DD}} < 2.7 \text{ V}$			9.0	mA
				1.6 V ≤ EV <sub>DD</sub> < 1.8 V			4.5	mA
		Total of P1	5 to P17, P30 to P32,	$4.0~V \leq EV_{DD} \leq 5.5~V$			80.0	mA
		P50 to P54	4, P60, P61, P70 to P74,	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}$			35.0	mA
			$y = 70\%^{\text{Note 2}}$	$1.8 \text{ V} \leq \text{EV}_{DD} < 2.7 \text{ V}$			20.0	mA
		,	,	1.6 V ≤ EV <sub>DD</sub> < 1.8 V			10.0	mA
			otal of all pins When duty = 70% Note 2) 20, P21 Per pin for				150.0	mA
	lo <sub>L2</sub>	P20, P21					0.4 Note 3	mA
			Total of all pins (When duty = 70% <sup>Note 2</sup> )	$1.6~V \leq V_{DD} \leq 5.5~V$			5.0	mA

- Notes 1. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the EVss and Vss pin.
  - 2. Specification under conditions where the duty factor is 70%.

The output current value that has changed the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

• Total output current of pins =  $(lol \times 0.7)/(n \times 0.01)$ 

<Example> Where n = 50% and IoL = 10.0 mA

Total output current of pins =  $(10.0 \times 0.7)/(50 \times 0.01) = 14.0 \text{ mA}$ 

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

3. Do not exceed the total current value.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(Ta = -40 to +85°C, 1.6 V  $\leq$  EVDD = VDD  $\leq$  5.5 V, Vss = EVss = 0 V)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	V <sub>IH1</sub>	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	Normal input buffer	0.8EV <sub>DD</sub>		EV <sub>DD</sub>	V
	V <sub>IH2</sub>	-, , -, -	TTL input buffer $4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}$	2.2		EV <sub>DD</sub>	V
			TTL input buffer $3.3 \text{ V} \leq \text{EV}_{DD} < 4.0 \text{ V}$	2.0		EV <sub>DD</sub>	V
			TTL input buffer $1.6~V \le EV_{DD} < 3.3~V$	1.50		EV <sub>DD</sub>	V
	VIH3	P20, P21		0.7V <sub>DD</sub>		V <sub>DD</sub>	V
	V <sub>IH4</sub>	P60, P61	0.7EV <sub>DD</sub>		6.0	٧	
	V <sub>IH5</sub>	P121 to P124, P137, EXCLK, EXCLKS	S, RESET	0.8V <sub>DD</sub>		V <sub>DD</sub>	٧
Input voltage, low	V <sub>IL1</sub>	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	Normal input buffer	0		0.2EV <sub>DD</sub>	V
	V <sub>IL2</sub>	P10, P11, P15, P16	TTL input buffer 4.0 V ≤ EV <sub>DD</sub> ≤ 5.5 V	0		0.8	V
			TTL input buffer $3.3 \text{ V} \leq \text{EV}_{DD} < 4.0 \text{ V}$	0		0.5	V
			TTL input buffer 1.6 V ≤ EV <sub>DD</sub> < 3.3 V	0		0.32	V
	V <sub>IL3</sub>	P20, P21		0		0.3V <sub>DD</sub>	V
	V <sub>IL4</sub>	P60, P61		0		0.3EV <sub>DD</sub>	V
	V <sub>IL5</sub>	P121 to P124, P137, EXCLK, EXCLK	S, RESET	0		0.2V <sub>DD</sub>	٧

Cautions The maximum value of ViH of P10, P12, P15, P17 is VDD, even in the N-ch open-drain mode.

**Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(Ta = -40 to +85°C, 1.6 V  $\leq$  EVDD = VDD  $\leq$  5.5 V, Vss = EVss = 0 V)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output voltage, high	V <sub>OH1</sub>	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120,	$4.0~V \leq EV_{DD} \leq 5.5~V,$ T.B.D.	T.B.D.			V
		P125 to P127, P130, P140 to P147	$4.0~V \leq EV_{DD} \leq 5.5~V,$ T.B.D.	T.B.D.			V
			$2.7~V \leq EV_{DD} \leq 5.5~V,$ T.B.D.	T.B.D.			V
			$1.8~V \leq EV_{DD} \leq 5.5~V,$ T.B.D.	T.B.D.			V
			$1.6 \text{ V} \le \text{EV}_{\text{DD}} < 5.5 \text{ V},$ T.B.D.	T.B.D.			V
	V <sub>OH2</sub>	P20, P21	$1.6~V \leq V_{DD} \leq 5.5~V,$ $T.B.D.$	T.B.D			V
Output voltage,	V <sub>OL1</sub>	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120,	$4.0~V \leq EV_{DD} \leq 5.5~V,$ T.B.D.			T.B.D.	V
		P125 to P127, P130, P140 to P147	$4.0~V \leq EV_{DD} \leq 5.5~V,$ T.B.D.			T.B.D.	V
			$2.7~V \leq EV_{DD} \leq 5.5~V,$ T.B.D.			T.B.D.	V
			$2.7~V \leq EV_{DD} \leq 5.5~V,$ T.B.D.			T.B.D.	V
			$1.8~V \leq EV_{DD} \leq 5.5~V,$ T.B.D.			T.B.D.	V
			$1.6 \text{ V} \le \text{EV}_{\text{DD}} < 5.5 \text{ V},$ T.B.D.			T.B.D.	V
	V <sub>OL2</sub>	P20, P21	$1.6~V \le V_{DD} \le 5.5~V,$ T.B.D.			T.B.D.	V
	Vol3	P60, P61	$4.0~V \leq EV_{DD} \leq 5.5~V,$ T.B.D.			T.B.D.	V
			$4.0~V \leq EV_{DD} \leq 5.5~V,$ T.B.D.			T.B.D.	V
			$2.7~V \leq EV_{DD} \leq 5.5~V,$ T.B.D.			T.B.D.	V
			$1.8~V \leq EV_{DD} \leq 5.5~V,$ $T.B.D.$			T.B.D.	V
			$1.6 \text{ V} \le \text{EV}_{\text{DD}} < 5.5 \text{ V},$ T.B.D.			T.B.D.	V

Caution P10, P12, P15, P17 do not output high level in N-ch open-drain mode.

**Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



(Ta = -40 to +85°C, 1.6 V  $\leq$  EVDD = VDD  $\leq$  5.5 V, Vss = EVss = 0 V)

Items	Symbol	Condition	ns		MIN.	TYP.	MAX.	Unit
Input leakage current, high	Ішн1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P140 to P147	$V_{I} = EV_{DD}$				1	μΑ
	I <sub>LIH2</sub>	P20, P21, P137, RESET	$V_{I} = V_{DD}$				1	μА
	Ішнз	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	VI = VDD	In input port or external clock input			1	μΑ
				In resonator connection			10	μΑ
Input leakage current, low	ILIL1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P140 to P147	Vı = EVss				-1	μΑ
	ILIL2	P20, P21, P137, RESET	Vı = Vss				-1	μΑ
	ILIL3	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	Vı = Vss	In input port or external clock input			-1	μΑ
				In resonator connection			-10	μΑ
On-chip pll-up resistance	R∪	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	V <sub>I</sub> = EVss,	In input port	10	20	100	kΩ

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

# 2.3.2 Supply current characteristics

#### (Ta = -40 to +85°C, 1.6 V $\leq$ EVDD = VDD $\leq$ 5.5 V, Vss = EVss = 0 V)

(1/2)

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply	IDD1 Note 1	Operating	High-speed	fin = 24 MHz Note 3	Basic	$V_{DD} = 5.0 \text{ V}$		1.8	T.B.D.	mA
current	nt mode operation Notes			operation	$V_{DD} = 3.0 \text{ V}$		1.8	T.B.D.	mA	
				Normal	$V_{DD} = 5.0 \text{ V}$		3.7	T.B.D.	mA	
					operation	V <sub>DD</sub> = 3.0 V		3.7	T.B.D.	mA
				fin = 16 MHz Note 3	Normal	V <sub>DD</sub> = 5.0 V		2.7	T.B.D.	mA
					operation V	V <sub>DD</sub> = 3.0 V		2.7	T.B.D.	mA
			Low-speed	fin = 8 MHz Note 3	Normal	$V_{DD} = 3.0 \text{ V}$		1.2	T.B.D.	mA
			operation Note 5		operation	V <sub>DD</sub> = 2.0 V		1.2	T.B.D.	mA
			Low-voltage	fin = 4 MHz Note 3	Normal	$V_{DD} = 3.0 \text{ V}$		1.2	T.B.D.	mA
			operation Note 5		operation	V <sub>DD</sub> = 2.0 V		1.2	T.B.D.	mA
	High-spee operation <sup>N</sup>	High-speed	$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$	Normal	Square wave input		3.0	T.B.D.	mA	
		operation Note 5	V <sub>DD</sub> = 5.0 V	operation	Resonator connection		3.2	T.B.D.	mA	
			$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$	Normal	Square wave input		3.0	T.B.D.	mA	
			V <sub>DD</sub> = 3.0 V	operation	Resonator connection		3.2	T.B.D.	mA	
				$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$	Normal operation	Square wave input		1.9	T.B.D.	mA
				V <sub>DD</sub> = 5.0 V		Resonator connection		1.9	T.B.D.	mA
			$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$	Normal	Square wave input		1.9	T.B.D.	mA	
				V <sub>DD</sub> = 3.0 V	operation	Resonator connection		1.9	T.B.D.	mA
			Low-speed	$f_{MX} = 8 MHz^{Note 2}$	Normal	Square wave input		1.1	T.B.D.	mA
			operation Note 5	V <sub>DD</sub> = 3.0 V	operation	Resonator connection		1.1	T.B.D.	mA
				$f_{MX} = 8 MHz^{Note 2}$	Normal	Square wave input		1.1	T.B.D.	mA
				V <sub>DD</sub> = 2.0 V	operation	Resonator connection		1.1	T.B.D.	mA
			Subsystem	fsuB = 32.768 kHz Note 4	Normal	Square wave input		4.1	T.B.D.	μA
			clock operation	T <sub>A</sub> = -40°C	operation	Resonator connection		4.2	T.B.D.	μA
			ореганоп	fsuB = 32.768 kHz Note 4	Normal	Square wave input		4.1	T.B.D.	μA
				T <sub>A</sub> = +25°C	operation	Resonator connection		4.2	T.B.D.	μA
				fsuB = 32.768 kHz Note 4	Normal	Square wave input		4.2	T.B.D.	μA
			T <sub>A</sub> = +50°C	operation	Resonator connection		4.3	T.B.D.	μA	
		f	fsuB = 32.768 kHz Note 4	Normal	Square wave input		4.2	T.B.D.	μA	
				operation	Resonator connection		4.3	T.B.D.	μΑ	
			fsu	fsuB = 32.768 kHz Note 4	Normal	Square wave input		4.8	T.B.D.	μΑ
				T <sub>A</sub> = +85°C	operation	Resonator connection		4.9	T.B.D.	μΑ

(Notes and Remarks are listed on the next page.)

- Notes 1. Total current flowing into VDD and EVDD, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD or Vss, EVss. The values below the MAX. column include the peripheral operation current (except for back ground operation (BGO)). However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors.
  - 2. When high-speed on-chip oscillator and subsystem clock are stopped.
  - 3. When high-speed system clock and subsystem clock are stopped.
  - 4. When high-speed on-chip oscillator and high-speed system clock are stopped. When real-time clock and watchdog timer are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation).
  - 5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as

High speed operation:  $V_{DD} = 2.4 \text{ V}$  to 5.5 V@1 MHz to 24 MHzLow speed operation:  $V_{DD} = 1.8 \text{ V to } 5.5 \text{ V@1 MHz to } 8 \text{ MHz}$ Low voltage operation: VDD = 1.6 V to 5.5 V@1 MHz to 4 MHz

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: High-speed on-chip oscillator clock frequency
  - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
  - 4. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C

# (Ta = -40 to +85°C, 1.6 V $\leq$ EVDD = VDD $\leq$ 5.5 V, Vss = EVss = 0 V)

(2/2)

Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	I <sub>DD2</sub>	HALT	High-speed	fin = 24 MHz Note 4	V <sub>DD</sub> = 5.0 V		0.44	T.B.D.	mA
current	Note 2	mode	operation Note 7		V <sub>DD</sub> = 3.0 V		0.44	T.B.D.	mA
				fin = 16 MHz Note 4	V <sub>DD</sub> = 5.0 V		0.40	T.B.D.	mA
					V <sub>DD</sub> = 3.0 V		0.40	T.B.D.	mA
			Low-speed	fih = 8 MHz Note 4	V <sub>DD</sub> = 3.0 V		260	T.B.D.	μA
			operation Note 7		V <sub>DD</sub> = 2.0 V		260	T.B.D.	μΑ
			Low-voltage	f <sub>IH</sub> = 4 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 3.0 V		420	T.B.D.	μΑ
			operation		V <sub>DD</sub> = 2.0 V		420	T.B.D.	μΑ
			High-speed	f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		0.28	T.B.D.	mA
			operation Note 7	V <sub>DD</sub> = 5.0 V	Resonator connection		0.45	T.B.D.	mA
				f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		0.28	T.B.D.	mA
				V <sub>DD</sub> = 3.0 V	Resonator connection		0.45	T.B.D.	mA
				fmx = 10 MHz <sup>Note 3</sup> ,	Square wave input		0.19	T.B.D.	mA
				V <sub>DD</sub> = 5.0 V	Resonator connection		0.26	T.B.D.	mA
				fmx = 10 MHz <sup>Note 3</sup> ,	Square wave input		0.19	T.B.D.	mA
			V <sub>DD</sub> = 3.0 V	Resonator connection		0.26	T.B.D.	mA	
			Low-speed	$f_{MX} = 8 MHz^{Note 3},$	Square wave input		95	T.B.D.	μA
			operation Note 7	V <sub>DD</sub> = 3.0 V	Resonator connection		145	T.B.D.	μA
				$f_{MX} = 8 MHz^{Note 3},$	Square wave input		95	T.B.D.	μA
				V <sub>DD</sub> = 2.0 V	Resonator connection		145	T.B.D.	μA
			Subsystem	fsub = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.32	T.B.D.	μA
			clock operation	T <sub>A</sub> = -40C	Resonator connection		0.51	T.B.D.	μA
			operation	fsub = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.37	T.B.D.	μA
				T <sub>A</sub> = +25°C	Resonator connection		0.56	T.B.D.	μA
				fsub = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.40	T.B.D.	μA
				T <sub>A</sub> = +50°C	Resonator connection		0.59	T.B.D.	μA
				fsub = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.43	T.B.D.	μA
				T <sub>A</sub> = +70°C	Resonator connection		0.62	T.B.D.	μA
				fsub = 32.768 kHz <sup>Note 5</sup>	Square wave input		1.04	T.B.D.	μA
				T <sub>A</sub> = +85°C	Resonator connection		1.23	T.B.D.	μA
	IDD3 <sup>Note 6</sup>	STOP	T <sub>A</sub> = -40°C				0.18	T.B.D.	μΑ
	mode $T_A = +25^{\circ}C$				0.23	T.B.D.	μΑ		
			$T_A = +50^{\circ}C$				0.26	T.B.D.	$\mu$ A
			T <sub>A</sub> = +70°C				0.29	T.B.D.	μΑ
			T <sub>A</sub> = +85°C				0.90	T.B.D.	μΑ

(Notes and Remarks are listed on the next page.)

- Notes 1. Total current flowing into VDD and EVDD, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD or Vss, EVss. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors.
  - 2. During HALT instruction execution by flash memory.
  - 3. When high-speed on-chip oscillator and subsystem clock are stopped.
  - 4. When high-speed system clock and subsystem clock are stopped.
  - 5. When operating real-time clock (RTC) and setting ultra-low current consumption (AMPHS1 = 1). When high-speed on-chip oscillator and high-speed system clock are stopped. When watchdog timer is stopped.
  - 6. When high-speed on-chip oscillator, high-speed system clock, and subsystem clock are stopped. When watchdog timer is stopped.
  - 7. Relationship between operation voltage width, operation frequency of CPU and operation mode is as

High speed operation: VDD = 2.4 V to 5.5 V@1 MHz to 24 MHz Low speed operation: VDD = 1.8 V to 5.5 V@1 MHz to 8 MHz Low voltage operation: VDD = 1.6 V to 5.5 V@1 MHz to 4 MHz

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: High-speed on-chip oscillator clock frequency
  - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
  - 4. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is TA = 25°C

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$

Parameter	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
RTC operating	IRTC Notes 1, 2	fsuв = 32.768 kHz	Real-time clock operation	1		0.02		μА
current			Interval timer operation			0.02		
Watchdog timer operating current	WDT Notes 2, 3	fı∟ = 15 kHz				0.22		μΑ
A/D converter	IADC Note 4		Normal mode, AVREFP = V	/ <sub>DD</sub> = 5.0 V		1.3	1.7	mA
operating current			Low voltage mode, AVREF	FP = VDD = 3.0 V		0.5	0.7	mA
Temperature sensor operating current	Ітмрѕ					75		μΑ
LVD operating current	ILVI Note 5					0.08		μА
BGO operating current	IBGO Note 6					2.50	12.20	mA
LCD operating current	ILCD1 Notes 7, 8	External resistance division method	LCD clock = 128 Hz	V <sub>DD</sub> = 5.0 V		T.B.D.	T.B.D.	μА
	ILCD2 Note7	Internal voltage boosting method	LCD clock = 128 Hz	V <sub>DD</sub> = 3.0 V		1.0	T.B.D.	μΑ
	ILCD3 Note7	Capacitor split method	LCD clock = 128 Hz	V <sub>DD</sub> = 3.0 V		0.12	T.B.D.	μΑ

- Notes 1. Current flowing only to the real-time clock (excluding the operating current of the XT1 oscillator). The TYP. value of the current value of the RL78/L12 is the sum of the TYP. values of either IDD1 or IDD2, and IRTC, when the real-time clock operates in operation mode or HALT mode. The IDD1 and IDD2 MAX. values also include the real-time clock operating current. However, IDD2 subsystem clock operation includes the operational current of the real-time clock.
  - 2. When high-speed on-chip oscillator and high-speed system clock are stopped.
  - 3. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The current value of the RL78/L12 is the sum of IDD1, IDD2 or IDD3 and IWDT when fCLK = fSUB when the watchdog timer operates in STOP mode.
  - 4. Current flowing only to the A/D converter. The current value of the RL78/L12 is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
  - 5. Current flowing only to the LVD circuit. The current value of the RL78/L12 is the sum of IDD1, IDD2 or IDD3 and ILVI when the LVD circuit operates in the Operating, HALT or STOP mode.
  - 6. Current flowing only when the BGO operates. The current value of the RL78/L12 is the sum of IDD1 or IDD2 and IBGO when the BGO operates in an operation mode.
  - 7. Current flowing only to the LCD controller/driver (VDD pin). The current value of the RL78/L12 microcontrollers is the sum of the LCD operating current (ILCD1, ILCD2 or ILCD3) to the supply current (IDD1, or IDD2) when the LCD controller/driver operates in an operation mode or HALT mode. Not including the current that flows through the LCD panel.
  - 8. Not including the current that flows through the LCD divider resistor.
- Remarks 1. fil: Low-speed on-chip oscillator clock frequency
  - 2. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
  - 3. fclk: CPU/peripheral hardware clock frequency
  - 4. Temperature condition of the TYP. value is TA = 25°C



#### 2.4 AC Characteristics

# 2.4.1 Basic operation

# (Ta = -40 to +85°C, 1.6 V $\leq$ EVDD = VDD $\leq$ 5.5 V, Vss = EVss = 0 V)

Items	Symbol		Conditio	ons		MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Тсч	Main	High-spee		$2.7 V \le V_{DD} \le 5.5 V$	0.04167		1	μS
instruction execution time)		system clock (fmain)	main mod	le -	$2.4 \text{ V} \le \text{V}_{DD} < 2.7 \text{ V}$	0.0625		1	μS
		operation	Low voltage	9 -	$1.6~V \le V_{DD} \le 5.5~V$	0.25		1	μS
			Low-spee main mod		$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$	0.125		1	μS
		Subsystem clock (fsub) 1.8 V ≤ VDD ≤ 5.5 Voperation		$1.8 V \le V_{DD} \le 5.5 V$	28.5	30.5	31.3	μS	
		In the self	High-spee		$2.7~V \le V_{DD} \le 5.5~V$	0.04167		1	μS
		programming mode	main mod	le	$2.4 \text{ V} \le \text{V}_{DD} < 2.7 \text{ V}$	0.0625		1	μS
			Low voltage		$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$	0.25		1	μS
			Low-spee main mod		$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$	0.125		1	μS
External main system clock	fex	$2.7 \text{ V} \leq V_{DD} \leq$				1.0		20.0	MHz
frequency		1.8 V ≤ V <sub>DD</sub> <				1.0		8.0	MHz
		1.6 V ≤ V <sub>DD</sub> <	< 1.8 V			1.0		4.0	MHz
	fexs					32		35	kHz
External main system clock input high-level width, low-level width	texh, texl	2.7 V ≤ V <sub>DD</sub> ≤				24			ns
mgn level main, lew level main		$1.8 \text{ V} \leq \text{V}_{DD} < 2.7 \text{ V}$		60			ns		
		1.6 V ≤ V <sub>DD</sub> <	6 V ≤ V <sub>DD</sub> < 1.8 V		120			ns	
	texhs, texhs					13.7			μS
TI00 to TI07 input high-level width, low-level width	tтін, tтіL					1/fмск+10			ns <sup>Note</sup>
TO00 to TO07 output frequency	fто	High-speed r	main 4.0	<b>V</b> ≤	$EV_{\text{DD}} \leq 5.5 \ V$			12	MHz
		mode	2.7	$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}$ $1.8 \text{ V} \le \text{EV}_{DD} < 2.7 \text{ V}$				8	MHz
			1.8					4	MHz
			1.6	1.6 V ≤ EV <sub>DD</sub> < 1.8 V				2	MHz
		Low voltage mode	w voltage main $1.6 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}$				2	MHz	
		Low-speed n	nain 1.8	V ≤	$EV_{DD} \leq 5.5 \ V$			4	MHz
		mode	1.6	V ≤	EV <sub>DD</sub> < 1.8 V			2	MHz
PCLBUZ0, PCLBUZ1 output	fpcL	High-speed r	main 4.0	V ≤	$EV_{DD} \leq 5.5 \; V$			16	MHz
frequency		mode	2.7	<b>V</b> ≤	EV <sub>DD</sub> < 4.0 V			8	MHz
			1.8	<b>V</b> ≤	$EV_{DD} < 2.7 V$			4	MHz
			1.6	<b>V</b> ≤	EV <sub>DD</sub> < 1.8 V			2	MHz
		Low voltage			$EV_{\text{DD}} \leq 5.5 \; V$			4	MHz
		mode			EV <sub>DD</sub> < 1.8 V			2	MHz
		Low-speed n mode			<b>EV</b> <sub>DD</sub> ≤ 5.5 <b>V</b>			4	MHz
					EV <sub>DD</sub> < 1.8 V			2	MHz
Interrupt input high-level width, low-level width	tinth, tintl	INTPO			V <sub>DD</sub> ≤ 5.5 V	1			μS
		INTP1 to INT			EV <sub>DD</sub> ≤ 5.5 V	1			μS
Key interrupt input low-level width	<b>t</b> kr	KR0 to KR3			EV <sub>DD</sub> ≤ 5.5 V	250			ns
RESET low-level width	too		1.6	v ≤	EV <sub>DD</sub> < 1.8 V	10			μS
NESET TOW-TEVEL WIGHT	trsl					10			μS

(Note and Remark are listed on the next page.)

Note The following conditions are required for low voltage interface when EVDD<VDD

 $1.8~\text{V} \leq \text{EV}_{\text{DD}} < 2.7~\text{V}$  : MIN. 125 ns  $1.6 \text{ V} \le \text{EV}_{\text{DD}} < 1.8 \text{ V}$ : MIN. 250 ns

Remark fmck: Timer array unit operation clock frequency

(Operation clock to be set by the CKS0n bit of timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))

#### **ELECTRICAL SPECIFICATIONS (TARGET)**

#### Caution The pins mounted depend on the product. Refer to 1.3.1 32-pin products to 1.3.5 64-pin products.

#### 2.5 Peripheral Functions Characteristics

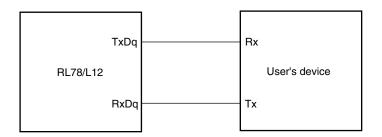
#### 2.5.1 Serial array unit

#### (1) During communication at same potential (UART mode) (dedicated baud rate generator output)

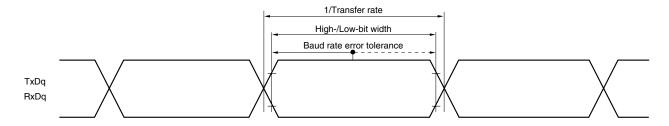
 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate Note 1					fmck/6 Note 2	bps
		Theoretical value of the maximum transfer rate fclk=24MHz, fmck= fclk			4.0	Mbps

#### **UART** mode connection diagram (during communication at same potential)



#### **UART** mode bit width (during communication at same potential) (reference)



- Notes 1. Transfer rate in the SNOOZE mode is max. 9600 bps, min. 4800 bps.
  - 2. The following conditions are required for low voltage interface when EvdD < VdD.

 $2.4 \text{ V} \leq \text{EV}_{\text{DD}} < 2.7 \text{ V}$ : MAX. 2.6 Mbps  $1.8 \text{ V} \leq \text{EV}_{\text{DD}} < 2.4 \text{ V}$ : MAX. 1.3 Mbps  $1.6~V \leq EV_{\text{DD}} < 1.8~V$  : MAX. 0.6 Mbps

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

**Remarks 1.** q: UART number (q = 0), g: PIM and POM number (g = 1)

2. fmck: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

# (2) During communication at same potential (CSI mode) (master mode (fmck/2, fmck/4), SCKp... internal clock output)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
SCKp cycle time	tkcy1	$2.7~V \leq EV_{DD} \leq 5.5~V$	167 Note 1			ns
		2.4 V ≤ EV <sub>DD</sub> ≤ 5.5 V	250 Note 1			ns
		1.8 V ≤ EV <sub>DD</sub> ≤ 5.5 V	500 Note 1			ns
		1.6 V ≤ EV <sub>DD</sub> ≤ 5.5 V	1000 Note 1			ns
SCKp high-/low-level width	tкн1,	$4.0~V \leq EV_{DD} \leq 5.5~V$	tkcy1/2 - 12			ns
	t <sub>KL1</sub>	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$	tkcy1/2 - 18			ns
		$2.4~V \leq EV_{DD} \leq 5.5~V$	tkcy1/2 - 38			ns
		$1.8~V \leq EV_{DD} \leq 5.5~V$	tkcy1/2 - 50			ns
		1.6 V ≤ EV <sub>DD</sub> ≤ 5.5 V	tксу1/2 — 100			ns
SIp setup time (to SCKp↑) Note 2	tsıĸ1	$4.0~V \leq EV_{DD} \leq 5.5~V$	44			ns
		$2.7~V \leq EV_{DD} \leq 5.5~V$	44			ns
		$2.4~V \leq EV_{DD} \leq 5.5~V$	75			ns
		1.8 V ≤ EV <sub>DD</sub> ≤ 5.5 V	110			ns
		1.6 V ≤ EV <sub>DD</sub> ≤ 5.5 V	220			ns
SIp hold time (from SCKp↑) Note 3	tksii		19			ns
Delay time from SCKp↓ to SOp output Note 4	tkso1	C = 30 pF <sup>Note 5</sup>			25	ns

Notes 1. For CSI00, set a cycle of 2/fclk or longer. For other than CSI00, set a cycle of 4/fclk or longer.

- 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from  $\overline{SCKp}\downarrow$ " when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **5.** C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

**Remarks 1.** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM numbers (g = 1)

2. fMCK: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

# (3) During communication at same potential (CSI mode) (slave mode, SCKp... external clock input) (T<sub>A</sub> = -40 to +85°C, 1.6 V ≤ EV<sub>DD</sub> = V<sub>DD</sub> ≤ 5.5 V, Vss = EV<sub>SS</sub> = 0 V)

Parameter	Symbol	Co	onditions	MIN.	TYP.	MAX.	Unit
SCKp cycle time Note 5	tkcy2	4.0 V ≤ EV <sub>DD</sub> ≤	20 MHz < fмск	8/fмск			ns
		5.5 V	fмск ≤ 20 MHz	6/fмск			ns
		2.7 V ≤ EV <sub>DD</sub> <	16 MHz < fмск	8/fмск			ns
		4.0 V	fмcк ≤ 16 MHz	6/fмск			ns
		1.8 V ≤ EV <sub>DD</sub> <	16 MHz < fмск	8/fмск			ns
		2.7 V	fмcк ≤ 16 MHz	6/fмск			ns
		1.6 V ≤ EV <sub>DD</sub> <	1.8 V	6/fмск			ns
SCKp high-/low-level width	tĸH2,	1.6 V ≤ EV <sub>DD</sub> ≤	5.5 V	tkcy2/2			ns
	tKL2						
SIp_setup time	tsık2	$2.7~V \leq EV_{DD} \leq 5.5~V$		1/fмск+20			ns
(to SCKp↑) Note 1		$1.8 \text{ V} \leq \text{EV}_{DD} < 2.7 \text{ V}$		1/fмск+30			ns
		1.6 V ≤ EV <sub>DD</sub> <	$1.6 \text{ V} \leq \text{EV}_{\text{DD}} < 1.8 \text{ V}$				ns
Slp hold time	tksi2	$2.7~V \leq EV_{DD} \leq$	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5 V				ns
(from SCKp↑) Note 2		1.8 V ≤ EV <sub>DD</sub> <	2.7 V	1/fмск+31			ns
		1.6 V ≤ EV <sub>DD</sub> <	1.8 V	1/fмск+ 250			ns
Delay time from SCKp↓ to	tkso2	C = 30 pF Note 4	$4.0~V \leq EV_{DD} \leq 5.5~V$			2/fмск+44	ns
SOp output Note 3			$2.7~V \leq EV_{DD} < 4.0~V$			2/fмск+44	ns
			$2.4~V \le EV_{DD} < 2.7~V$			2/fмск+75	ns
			$1.8 \text{ V} \le \text{EV}_{\text{DD}} < 2.4 \text{ V}$			2/fмск+110	ns
			1.6 V ≤ EV <sub>DD</sub> < 1.8 V			2/fмск+ 220	ns

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 4. C is the load capacitance of the SOp output lines.
  - 5. Transfer rate in the SNOOZE mode: MAX. 1 Mbps

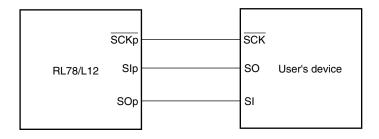
Caution Select the TTL input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

**Remarks** 1. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM number (g = 1)

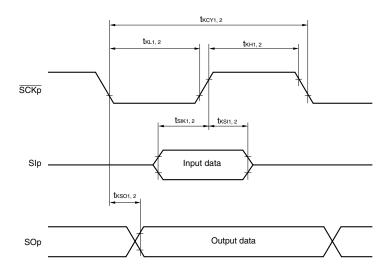
2. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

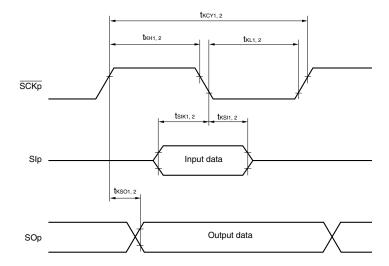
CSI mode connection diagram (during communication at same potential)



CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



**Remarks 1.** p: CSI number (p = 00, 01)

2. m: Unit number, n: Channel number (mn = 00, 01)

# (4) Communication at different potential (2.5 V, 3 V) (UART mode) (dedicated baud rate generator output) (1/2) $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \leq \text{EV}_{DD} = \text{V}_{DD} \leq 5.5 \text{ V}, \text{Vss} = \text{EVss} = 0 \text{ V})$

Parameter	Symbol		Conditio	ns	MIN.	TYP.	MAX.	Unit
Transfer rate		reception	$4.0 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V},$				fmck/6 <sup>Note 1</sup>	bps
			$2.7~V \leq V_b \leq 4.0~V$	Theoretical value of the maximum transfer rate fclk = 24 MHz, fmck = fclk			4.0	Mbps
			$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$				fmck/6 <sup>Note 1</sup>	bps
			$2.3~V \leq V_b \leq 2.7~V$	Theoretical value of the maximum transfer rate fclk = 24 MHz, fMck = fclk			4.0	Mbps
			$1.8 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V},$ $1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}$				fMCK/6 Notes 1 to 3	bps
				Theoretical value of the maximum transfer rate			1.3	Mbps
				fclk = 8 MHz, fmck = fclk				

Notes 1. Transfer rate in the SNOOZE mode: MAX. 9600 bps, MIN. 4800 bps

2. Use it with EVDD≥Vb.

**3.** The following conditions are required for low voltage interface when EVDD<VDD.

 $2.4 \text{ V} \le \text{EV}_{\text{DD}} < 2.7 \text{ V}$ : MAX. 2.6 Mbps  $1.8 \text{ V} \le \text{EV}_{\text{DD}} < 2.4 \text{ V}$ : MAX. 1.3 Mbps  $1.6 \text{ V} \le \text{EV}_{\text{DD}} < 1.8 \text{ V}$ : MAX. 0.6 Mbps

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. V<sub>b</sub>[V]: Communication line voltage

- **2.** q: UART number (q = 0), g: PIM and POM number (g = 1)
- 3. fmck: Serial array unit operation clock frequency(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,n: Channel number (mn = 00, 01)
- **4.** V<sub>IH</sub> and V<sub>IL</sub> below are observation points for the AC characteristics of the serial array unit when communicating at different potentials in UART mode.

$$\begin{split} 4.0 \ V & \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V; \ V_{IH} = 2.2 \ V, \ V_{IL} = 0.8 \ V \\ 2.7 \ V & \leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V; \ V_{IH} = 2.0 \ V, \ V_{IL} = 0.5 \ V \\ 1.8 \ V & \leq EV_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V; \ V_{IH} = 1.50 \ V, \ V_{IL} = 0.32 \ V \end{split}$$

(4) Communication at different potential (2.5 V, 3 V) (UART mode) (dedicated baud rate generator output) (2/2)  $= -40 \text{ to } +85^{\circ}\text{C}$  18 V < FVpp = Vpp < 5.5 V Vss = FVss = 0 V)

Parameter	Symbol		Condi	tions	MIN.	TYP.	MAX.	Unit
Transfer rate		transmission	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V}$				Notes 1, 2	bps
				Theoretical value of the maximum transfer rate			2.8 Note 3	Mbps
				$C_b = 50 \text{ pF}, R_b = 1.4 \text{ k}\Omega, V_b = 2.7 \text{ V}$				
			$2.7 \text{ V} \le \text{EV}_{\text{DD}} < 4.0 \text{ V},$				Notes	bps
			$2.3 \text{ V} \le V_b \le 2.7 \text{ V}$				2, 4	
				Theoretical value of the maximum transfer rate			1.2 Note 5	Mbps
				$C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega, V_b = 2.3 \text{ V}$				
			$1.8 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V},$				Notes	bps
			$1.6 \text{ V} \le V_b \le 2.0 \text{ V}$				2, 6, 7	
				Theoretical value of the maximum transfer rate			0.43 Notes 8	Mbps
				$C_b = 50 \text{ pF}, R_b = 5.5 \text{ k}\Omega, V_b = 1.6 \text{ V}$				

Notes 1. The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V  $\leq$  EV<sub>DD</sub>  $\leq$  5.5 V and 2.7 V  $\leq$  V<sub>b</sub>  $\leq$  4.0 V

Maximum transfer rate = 
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\} \times 3}$$
 [bps]

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln{(1 - \frac{2.2}{V_b})}\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- 2. Transfer rate in the SNOOZE mode: MAX. 9600 bps, MIN. 4800 bps
- 3. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 1 above to calculate the maximum transfer rate under conditions of the customer.
- 4. The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V  $\leq$  EV<sub>DD</sub> < 4.0 V and 2.3 V  $\leq$  V<sub>b</sub>  $\leq$  2.7 V

$$\text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \text{In } (1 - \frac{2.0}{V_b})\} \times 3} \quad \text{[bps]}$$

Baud rate error (theoretical value) = 
$$\frac{\frac{1}{|\text{Transfer rate} \times 2|} - \{-C_b \times R_b \times \ln(1 - \frac{2.0}{|V_b|})\}}{\frac{1}{|\text{Transfer rate}|} \times \text{Number of transferred bits}} \times 100 \text{ [%]}$$

- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- 5. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 4 above to calculate the maximum transfer rate under conditions of the customer.



#### **Notes 6.** Use it with $EV_{DD} \ge V_b$ .

7. The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate

Expression for calculating the transfer rate when 1.8 V  $\leq$  EV<sub>DD</sub> < 3.3 V and 1.6 V  $\leq$  V<sub>b</sub>  $\leq$  2.0 V

Maximum transfer rate = 
$$\frac{1}{\{-C_b \times R_b \times ln (1 - \frac{1.5}{V_b})\} \times 3}$$
 [bps]

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln{(1 - \frac{1.5}{V_b})}\}}{\frac{1}{\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

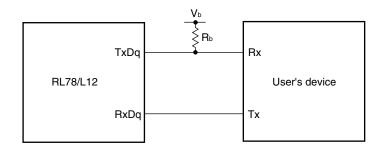
- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- **8.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 7 above to calculate the maximum transfer rate under conditions of the customer.

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

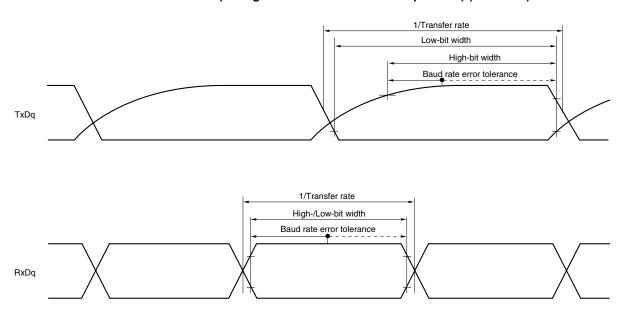
- **Remarks 1.** R<sub>b</sub>[ $\Omega$ ]:Communication line (TxDq) pull-up resistance, C<sub>b</sub>[F]: Communication line (TxDq) load capacitance, V<sub>b</sub>[V]: Communication line voltage
  - 2. q: UART number (q = 0, 1), g: PIM and POM number (g = 1)
  - 3. fmck: Serial array unit operation clock frequency(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).m: Unit number, n: Channel number (mn = 00, 01))
  - **4.** V<sub>IH</sub> and V<sub>IL</sub> below are observation points for the AC characteristics of the serial array unit when communicating at different potentials in UART mode.

$$\begin{split} 4.0 \ V &\leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V; \ V_{IH} = 2.2 \ V, \ V_{IL} = 0.8 \ V \\ 2.7 \ V &\leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V; \ V_{IH} = 2.0 \ V, \ V_{IL} = 0.5 \ V \\ 1.8 \ V &\leq EV_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V; \ V_{IH} = 1.50 \ V, \ V_{IL} = 0.32 \ V \end{split}$$

### **UART** mode connection diagram (during communication at different potential)



### UART mode bit width (during communication at different potential) (reference)



Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

**Remarks 1.**  $R_b[\Omega]$ : Communication line (TxDq) pull-up resistance,  $V_b[V]$ : Communication line voltage

**2.** q: UART number (q = 0), g: PIM and POM number (g = 1)

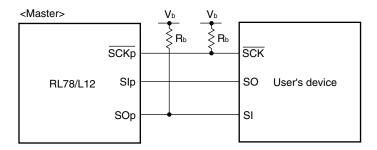
## (5) Communication at different potential (2.5 V, 3 V) (fMck/2) (CSI mode) (master mode, SCKp... internal clock output)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}. 2.7 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}. \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
SCKp cycle time	tkcy1	$4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V,$	200 Note 1			ns
		$C_b = 20 \text{ pF}, R_b = 1.4 \text{ k}\Omega$				
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	300 Note 1			ns
		$C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$				
SCKp high-level width	t <sub>KH1</sub>	$4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V,$	tkcy1/2 - 50			ns
		$C_b = 20 \text{ pF}, R_b = 1.4 \text{ k}\Omega$				
		$2.7 \ V \leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V,$	tkcy1/2 -			ns
		$C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	120			
SCKp low-level width	t <sub>KL1</sub>	$4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V,$	tkcy1/2 - 7			ns
		$C_b = 20 \text{ pF}, R_b = 1.4 \text{ k}\Omega$				
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	tkcy1/2 - 10			ns
		$C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$				
SIp setup time	tsık1	$4.0~V \le EV_{DD} \le 5.5~V,~2.7~V \le V_b \le 4.0~V,$	58			ns
(to SCKp↑) Note 2		$C_b = 20 \text{ pF}, R_b = 1.4 \text{ k}\Omega$				
		$2.7~V \le EV_{DD} < 4.0~V,  2.3~V \le V_b \le 2.7~V,$	121			ns
		$C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$				
SIp hold time	tksi1	$4.0~V \le EV_{DD} \le 5.5~V,~2.7~V \le V_b \le 4.0~V,$	10			ns
$(from \overline{SCKp}^{\uparrow})^{Note 2}$		$C_b = 20 \text{ pF}, R_b = 1.4 \text{ k}\Omega$				
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	10			ns
		$C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$				
Delay time from SCKp↓ to	tkso1	$4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V,$			60	ns
SOp output Note 2		$C_b = 20 \text{ pF}, R_b = 1.4 \text{ k}\Omega$				
		$2.7~V \le EV_{DD} < 4.0~V,  2.3~V \le V_b \le 2.7~V,$			130	ns
		$C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$				
SIp setup time	tsik1	$4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V,$	23			ns
(to SCKp↓) Note 3		$C_b = 20$ pF, $R_b = 1.4$ k $\Omega$				
		$2.7~V \le EV_{DD} < 4.0~V,  2.3~V \le V_b \le 2.7~V,$	33			ns
		$C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$				
SIp hold time	tksi1	$4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V,$	10			ns
$(from \overline{SCKp}^{\downarrow})^{Note 3}$		$C_b = 20 \text{ pF}, R_b = 1.4 \text{ k}\Omega$				
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	10			ns
		$C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$				
Delay time from SCKp↑ to	tkso1	$4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V,$			10	ns
SOp output Note 3		$C_b = 20$ pF, $R_b = 1.4$ k $\Omega$				
		$2.7~V \le EV_{DD} < 4.0~V,~2.3~V \le V_b \le 2.7~V,$			10	ns
		$C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$				

(Note, Caution and Remark are listed on the next page.)

CSI mode connection diagram (during communication at different potential)



Notes 1. The value must also be 2/fclk or more.

- 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
- 3. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

**Remarks 1.** R<sub>b</sub>[ $\Omega$ ]:Communication line ( $\overline{SCKp}$ , SOp) pull-up resistance, C<sub>b</sub>[F]: Communication line ( $\overline{SCKp}$ , SOp) load capacitance, V<sub>b</sub>[V]: Communication line voltage

- 2. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
- **3.** V<sub>IH</sub> and V<sub>IL</sub> below are observation points for the AC characteristics of the serial array unit when communicating at different potentials in CSI mode.

$$\begin{split} 4.0 \ V &\leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V; \ V_{IH} = 2.2 \ V, \ V_{IL} = 0.8 \ V \\ 2.7 \ V &\leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V; \ V_{IH} = 2.0 \ V, \ V_{IL} = 0.5 \ V \\ 1.8 \ V &\leq EV_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V; \ V_{IH} = 1.50 \ V, \ V_{IL} = 0.32 \ V \end{split}$$

4. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01)

### Specifications in this document are tentative and subject to change. **ELECTRICAL SPECIFICATIONS (TARGET)**

Caution The pins mounted depend on the product. Refer to 1.3.1 32-pin products to 1.3.5 64-pin products.

(6) Communication at different potential (2.5 V, 3 V) (fmck/4) (CSI mode) (master mode, SCKp... internal clock output) (1/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
SCKp cycle time	tkcy1	$4.0~V \leq EV_{DD} \leq 5.5~V,~2.7~V \leq V_b \leq 4.0~V,$	300 Note			ns
		$C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$				
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	500 Note			ns
		$C_b = 30$ pF, $R_b = 2.7$ k $\Omega$				
		$2.7 \; V \leq EV_{DD} < 3.3 \; V, \; 1.6 \; V \leq V_b \leq 2.0 \; V, \;$	1150 Note			ns
		$C_b = 30$ pF, $R_b = 5.5$ k $\Omega$				
SCKp high-level width	t <sub>KH1</sub>	$4.0~V \leq EV_{DD} \leq 5.5~V,~2.7~V \leq V_b \leq 4.0~V,$	tkcy1/2 - 75			ns
		$C_b = 30$ pF, $R_b = 1.4$ k $\Omega$				
		$2.7 \; V \leq EV_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V,$	tkcy1/2 -			ns
		$C_b = 30$ pF, $R_b = 2.7$ k $\Omega$	170			
		$1.8 \ V \leq EV_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V,$	tkcy1/2 -			ns
		$C_b = 30$ pF, $R_b = 5.5$ k $\Omega$	458			
SCKp low-level width	t <sub>KL1</sub>	$4.0 \; V \leq EV_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \;$	tkcy1/2 - 12			ns
		$C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$				
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	tkcy1/2 - 18			ns
		$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$				
		$1.8 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$	tkcy1/2 - 50			ns
		$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$				

**Note** The value must also be 4/fclk or more.

- Cautions 1. Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).
  - 2. Use it with EVDD ≥ Vb.
- Remarks 1. R<sub>b</sub>[Ω]:Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub>[F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub>[V]: Communication line voltage
  - 2. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
  - 3. VIH and VIL below are observation points for the AC characteristics of the serial array unit when communicating at different potentials in CSI mode.

$$4.0~V \leq EV_{\text{DD}} \leq 5.5~V,~2.7~V \leq V_{\text{b}} \leq 4.0~V;~V_{\text{IH}}$$
 =  $2.2~V,~V_{\text{IL}}$  =  $0.8~V$ 

$$2.7~V \leq EV_{DD} < 4.0~V,~2.3~V \leq V_b \leq 2.7~V;~V_{IH}$$
 =  $2.0~V,~V_{IL}$  =  $0.5~V$ 

$$1.8 \text{ V} \le \text{EV}_{\text{DD}} < 3.3 \text{ V}, \ 1.6 \text{ V} \le \text{V}_{\text{b}} \le 2.0 \text{ V}; \ \text{V}_{\text{IH}} = 1.50 \text{ V}, \ \text{V}_{\text{IL}} = 0.32 \text{ V}$$

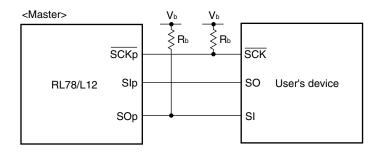
## (6) Communication at different potential (2.5 V, 3 V) (fMck/4) (CSI mode) (master mode, SCKp... internal clock output) (2/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
SIp setup time	tsık1	$4.0~V \leq EV_{DD} \leq 5.5~V,~2.7~V \leq V_b \leq 4.0~V,$	81			ns
(to SCKp↑) Note 1		$C_b = 30$ pF, $R_b = 1.4$ k $\Omega$				
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	177			ns
		$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$				
		$1.8 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$	479			ns
		$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$				
SIp hold time	t <sub>KSI1</sub>	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le V_b \le 4.0 \text{ V},$	19			ns
(from SCKp↑) Note 1		$C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$				
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	19			ns
		$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$				
		$1.8 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$	19			ns
		$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$				
Delay time from SCKp↓ to	tkso1	$4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V,$			100	ns
SOp output Note 1		$C_b = 30$ pF, $R_b = 1.4$ k $\Omega$				
		$2.7 \; V \leq EV_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V,$			195	ns
		$C_b = 30$ pF, $R_b = 2.7$ k $\Omega$				
		$1.8 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$			483	ns
		$C_b = 30 \text{ pF, } R_b = 5.5 \text{ k}\Omega$				
SIp setup time	tsık1	$4.0~V \leq EV_{DD} \leq 5.5~V,~2.7~V \leq V_b \leq 4.0~V,$	44			ns
(to SCKp↓) Note 2		$C_b = 30$ pF, $R_b = 1.4$ k $\Omega$				
		$2.7 \; V \leq EV_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V,$	44			ns
		$C_b = 30$ pF, $R_b = 2.7$ k $\Omega$				
		$1.8 \ V \leq EV_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V,$	110			ns
		$C_b = 30$ pF, $R_b = 5.5$ k $\Omega$				
SIp hold time	t <sub>KSI1</sub>	$4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V,$	19			ns
(from SCKp↓) Note 2		$C_b = 30$ pF, $R_b = 1.4$ k $\Omega$				
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	19			ns
		$C_b = 30 \text{ pF, } R_b = 2.7 \text{ k}\Omega$				
		$1.8 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$	19			ns
		$C_b = 30$ pF, $R_b = 5.5$ k $\Omega$				
Delay time from SCKp↑ to	tkso1	$4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V,$			25	ns
SOp output Note 2		$C_b = 30$ pF, $R_b = 1.4$ k $\Omega$				
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$			25	ns
		$C_b = 30$ pF, $R_b = 2.7$ k $\Omega$				
		$1.8 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V}, \ 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$			25	ns
		$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$				

(Note, Caution and Remark are listed on the next page.)

CSI mode connection diagram (during communication at different potential)



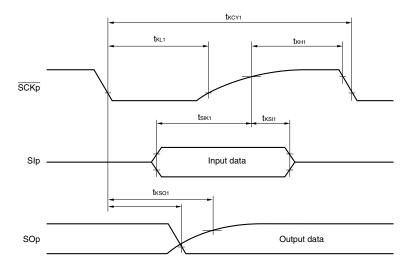
- **Notes 1.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
  - 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Cautions 1. Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).
  - 2. Use it with EVDD ≥ Vb.
- Remarks 1. R<sub>b</sub>[Ω]:Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub>[F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub>[V]: Communication line voltage
  - 2. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
  - 3. VIH and VIL below are observation points for the AC characteristics of the serial array unit when communicating at different potentials in CSI mode.

$$4.0~V \leq EV_{DD} \leq 5.5~V,~2.7~V \leq V_b \leq 4.0~V;~V_{IH}$$
 =  $2.2~V,~V_{IL}$  =  $0.8~V$ 

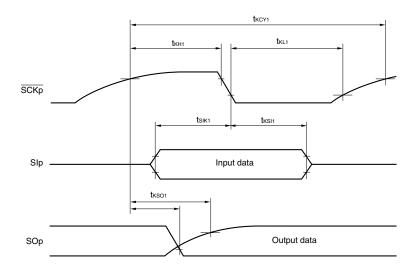
$$2.7~V \leq EV_{DD} < 4.0~V,~2.3~V \leq V_b \leq 2.7~V;~V_{IH}$$
 =  $2.0~V,~V_{IL}$  =  $0.5~V$ 

$$1.8~V \le EV_{DD} < 3.3~V,~1.6~V \le V_b \le 2.0~V;~V_{IH} = 1.50~V,~V_{IL} = 0.32~V$$

CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

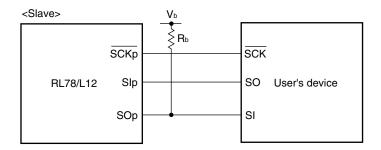
**Remark** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)

(7) Communication at different potential (2.5 V, 3 V) (CSI mode) (slave mode, SCKp... external clock input)  $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
SCKp cycle time Note 1	tkcy2	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$	20 MHz < fмck ≤ 24 MHz	12/fмск			ns
		$2.7 \ V \leq V_b \leq 4.0 \ V$	8 MHz < fмck ≤ 20 MHz	10/fмск			ns
			4 MHz < fmck ≤ 8 MHz	8/fмск			ns
			fмcк ≤ 4 MHz	6/fмск			ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD}} < 4.0 \text{ V},$	20 MHz < fмcк ≤ 24 MHz	<b>16/f</b> мск			ns
		$2.3 \ V \leq V_b \leq 2.7 \ V$	16 MHz < fмcк ≤ 20 MHz	14/fмск			ns
			8 MHz < fмcк ≤ 16 MHz	12/fмск			ns
			4 MHz < fмcк ≤ 8 MHz	8/fмск			ns
			fмcк ≤ 4 MHz	6/ƒмск			ns
		$1.8 \text{ V} \le \text{EV}_{\text{DD}} < 3.3 \text{ V},$	20 MHz < fмcк ≤ 24 MHz	36/fмск			ns
		$1.6~V \! \leq \! V_b \! \leq \! 2.0~V^{\text{Note 2}}$	16 MHz < fмcк ≤ 20 MHz	32/fмск			ns
			8 MHz < fмcк ≤ 16 MHz	26/fмск			ns
			4 MHz < fмcк ≤ 8 MHz	<b>16/f</b> мск			ns
			$f_{MCK} \le 4 \text{ MHz}$	10/fмск			ns
SCKp high-/low-level width Note 2	tkH2,	$4.0~V \leq EV_{DD} \leq 5.5$	$V,2.7~V \leq V_b \leq 4.0~V$	tkcy2/2 - 12			ns
		2.7 V ≤ EV <sub>DD</sub> < 4.0	tkcy2/2 – 18			ns	
		1.8 V ≤ EV <sub>DD</sub> < 3.3	$V, 1.6 \ V \le V_b \le 2.0 \ V$	tkcy2/2 - 50			ns
SIp setup time	tsik2	$2.7 \text{ V} \le \text{V}_{DD} < 5.5 \text{ V}$		1/fмcк + 20			ns
(to SCKp↑) Note 3		$1.8~V \leq V_b \leq 3.3~V$		1/fмcк + 30			ns
SIp hold time (from SCKp↑) Note 4	tksi2			1/fмcк + 31			ns
Delay time from SCKp↓ to	tkso2	$4.0~V \leq EV_{DD} \leq 5.5$	$V, 2.7 V \le V_b \le 4.0 V,$			2/fмск +	ns
SOp output Notes 2, 5		C <sub>b</sub> = 30 pF, R <sub>b</sub> = 1.	4 kΩ			120	
		$2.7~\textrm{V} \leq \textrm{EV}_\textrm{DD} < 4.0$	$V, 2.3 V \le V_b \le 2.7 V,$			2/fмск +	ns
		$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$				214	
		$1.8 \text{ V} \leq \text{EV}_{\text{DD}} < 3.3$	$V, 1.6 V \le V_b \le 2.0 V,$		, <u> </u>	2/fмск +	ns
		$C_b = 30 \text{ pF}, R_b = 5.5$	5 kΩ			573	

(Note, Caution and Remark are listed on the next page.)

### CSI mode connection diagram (during communication at different potential)



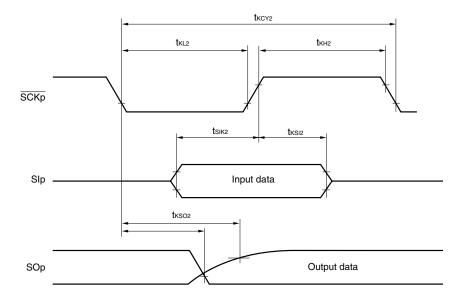
- Notes 1. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
  - **2.** Use it with EV<sub>DD</sub>  $\geq$  V<sub>b</sub>.
  - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 5. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

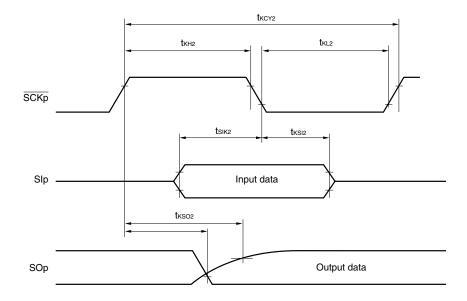
- **Remarks 1.** R<sub>b</sub>[Ω]:Communication line (SOp) pull-up resistance, C<sub>b</sub>[F]: Communication line (SOp) load capacitance, V<sub>b</sub>[V]: Communication line voltage
  - 2. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
  - 3. fmck: Serial array unit operation clock frequency(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).m: Unit number, n: Channel number (mn = 00, 01))
  - **4.** V<sub>IH</sub> and V<sub>IL</sub> below are observation points for the AC characteristics of the serial array unit when communicating at different potentials in CSI mode.

$$\begin{split} 4.0 \ V &\leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V; \ V_{IH} = 2.2 \ V, \ V_{IL} = 0.8 \ V \\ 2.7 \ V &\leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V; \ V_{IH} = 2.0 \ V, \ V_{IL} = 0.5 \ V \\ 1.8 \ V &\leq EV_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V; \ V_{IH} = 1.50 \ V, \ V_{IL} = 0.32 \ V \end{split}$$

CSI mode serial transfer timing (slave mode) (during communication at different potential)
(When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (slave mode) (during communication at different potential)
(When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

**Remark** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)

# Specifications in this document are tentative and subject to change. 2. ELECTRICAL SPECIFICATIONS (TARGET)

# Caution The pins mounted depend on the product. Refer to 1.3.1 32-pin products to 1.3.5 64-pin products.

### 2.5.2 Serial interface IICA

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

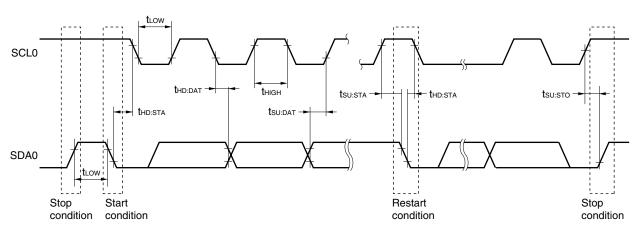
Parameter	Symbol	Conditions		Standard Mode		Fast Mode		Fast Mode Plus		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fscL	Fast mode plus: fcLk≥ 10 MHz	$2.7~\text{V} \leq \text{EV}_{\text{DD}} \leq 5.5~\text{V}$					0	1000	kHz
		Fast mode: fcLk ≥ 3.5 MHz	$1.8~V \leq EV_{DD} \leq 5.5~V$			0	400			kHz
		Normal mode: fclk≥ 1 MHz	$1.6~V \le EV_{DD} \le 5.5~V$	0	100					kHz
Setup time of restart conditionNote 1	tsu:sta			4.7		0.6		0.26		μS
Hold time	thd:STA			4.0		0.6		0.26		μS
Hold time when SCLA0 = "L"	tLOW			4.7		1.3		0.5		μS
Hold time when SCLA0 = "H"	tніgн			4.0		0.6		0.26		μS
Data setup time (reception)	tsu:dat			250		100		50		ns
Data hold time (transmission) <sup>Note 2</sup>	thd:dat			0	3.45	0	0.9	0		μS
Setup time of stop condition	tsu:sto			4.0		0.6		0.26		μS
Bus-free time	<b>t</b> BUF			4.7		1.3		0.5		μS

- Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.
  - 2. The maximum value (MAX.) of thd:DAT is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

**Remark** The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

 $\label{eq:cb} \begin{array}{ll} \mbox{Standard mode:} & C_b = 400 \mbox{ pF, } R_b = 2.7 \mbox{ } k\Omega \\ \mbox{Fast mode:} & C_b = 320 \mbox{ pF, } R_b = 1.1 \mbox{ } k\Omega \\ \mbox{Fast mode plus:} & C_b = 120 \mbox{ pF, } R_b = 1.1 \mbox{ } k\Omega \end{array}$ 

### **IICA** serial transfer timing



#### 2.5.3 On-chip debug (UART)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate			115.2 k		1 M	bps

### 2.6 Analog Characteristics

### 2.6.1 A/D converter characteristics

(1) When AVREF (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), AVREF (-) = AVREFM/ANI1 (ADREFM = 1), target ANI pin: ANI16 to ANI23 (supply ANI pin to EVDD)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \ 1.6 \text{ V} \leq \text{EV}_{DD} = \text{V}_{DD} \leq 5.5 \text{ V}, \ \text{Vss} = \text{EV}_{SS} = 0 \text{ V}, \ \text{Reference voltage (+)} = \text{AV}_{REFP}, \ \text{Reference voltage (+)} = \text{AV}_{REFP}$ voltage (-) = AVREFM)

Parameter	Symbol	Cond	ditions	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		10	bit
Overall error <sup>Notes 1, 2</sup>	AINL	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$		1.2	±5.0	LSB
		$AV_{REFP} = V_{DD}$	$1.6~V \leq V_{DD} \leq 5.5~V$		1.2	±8.5	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.125		39	μS
		$AV_{REFP} = V_{DD}$	$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μS
			$1.8~V \leq V_{DD} \leq 5.5~V$	17		39	μS
			$1.6~V \leq V_{DD} \leq 5.5~V$	57		95	μS
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution	$1.8~V \le V_{DD} \le 5.5~V$			±0.35	%FSR
		$AV_{REFP} = V_{DD}$	$1.6~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
Full-scale error <sup>Notes 1, 2</sup>	EFS	10-bit resolution	1.8 V ≤ VDD ≤ 5.5 V			±0.35	%FSR
		$AV_{REFP} = V_{DD}$	$1.6~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
Integral linearity errorNote 1	ILE	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±3.5	LSB
		$AV_{REFP} = V_{DD}$	$1.6~V \leq V_{DD} \leq 5.5~V$			±6.0	LSB
Differential linearity error Note 1	DLE	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±2.0	LSB
		$AV_{REFP} = V_{DD}$	$1.6~V \leq V_{DD} \leq 5.5~V$			±2.5	LSB
Reference voltage (+)	AVREFP			1.6		V <sub>DD</sub>	V
Analog input voltage	VAIN			0		AVREFP and EVDD	V
	V <sub>BGR</sub> Note3	$2.4~V \leq V_{DD} \leq 5.5~V$		1.38	1.45	1.5	٧

**Notes 1.** Excludes quantization error ( $\pm 1/2$  LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. HS (high-speed main) mode only

(2) When AVREF(+) = VDD (ADREFP1 = 0, ADREFP0 = 0), AVREF(-) = Vss (ADREFM = 0), target ANI pin : ANIO, ANI1, ANI16 to ANI23

(TA = -40 to +85°C, 1.6 V  $\leq$  EVDD = VDD  $\leq$  5.5 V, Vss = EVss = 0 V, Reference voltage (+) = VDD, Reference voltage (-) = Vss)

Parameter	Symbol	Con	ditions	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		10	bit
Overall error <sup>Notes 1, 2</sup>	AINL	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$		1.2	±7.0	LSB
			$1.6~V \leq V_{DD} \leq 5.5~V$		1.2	±10.5	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.125		39	μs
			$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μS
			$1.8~V \leq V_{DD} \leq 5.5~V$	17		39	μs
			$1.6~V \leq V_{DD} \leq 5.5~V$	57		95	μS
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
			$1.6~V \leq V_{DD} \leq 5.5~V$			±0.85	%FSR
Full-scale error <sup>Notes 1, 2</sup>	EFS	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
			$1.6~V \leq V_{DD} \leq 5.5~V$			±0.85	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±4.0	LSB
			$1.6~V \leq V_{DD} \leq 5.5~V$			±6.5	LSB
Differential linearity error Note 1	DLE	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±2.0	LSB
			$1.6~V \leq V_{DD} \leq 5.5~V$			±2.5	LSB
Analog input voltage	VAIN	ANIO, ANI1		0		V <sub>DD</sub>	V
		ANI16 to ANI23		0		EV <sub>DD</sub>	V
	V <sub>BGR</sub> Note3	$2.4~V \leq V_{DD} \leq 5.5~V$		1.38	1.45	1.5	V

**Notes 1.** Excludes quantization error (±1/2 LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. HS (high-speed main) mode only

(3) When AVREF (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), AVREF (-) = AVREFM/ANI1 (ADREFM = 1), target ANI pin : ANI0, ANI16 to ANI23

(TA = -40 to +85°C, 2.4 V  $\leq$  EVDD = VDD  $\leq$  5.5 V, Vss = EVss = 0 V, Reference voltage (+) = VBGR, Reference voltage (-) = AVREFM = 0 V) (HS (high-speed main) mode only)

Parameter	Symbol	Co	onditions	MIN.	TYP.	MAX.	Unit
Resolution	Res			8			bit
Conversion time	tconv	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μS
Zero-scale error <sup>Notes 1, 2</sup>	EZS	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±1.0	LSB
Reference voltage (+)	V <sub>BGR</sub>			1.38	1.45	1.5	V
Reference voltage (-)	AVREFM				Vss		V
Analog input voltage	VAIN			0		V <sub>BGR</sub>	V

**Notes 1.** Excludes quantization error ( $\pm 1/2$  LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

## 2.6.2 Temperature sensor characteristics

### (TA = -40 to +85°C, 2.4 V $\leq$ EVDD = VDD $\leq$ 5.5 V, Vss = EVss = 0 V) (HS (high-speed main) mode only)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	V <sub>TMPS25</sub>	Setting ADS register = 80H, Ta = +25°C		1.05		V
Reference output voltage	VCONST	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	FVTMPS	Temperature sensor that depends on the temperature		-3.6		mV/C
Operation stabilization wait time	tamp				5	μS

### 2.6.3 POR circuit characteristics

### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{ Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VPOR	Power supply rise time	1.48	1.51	1.54	٧
	V <sub>PDR</sub>	Power supply fall time	1.47	1.50	1.53	V
Minimum pulse width	T <sub>PW</sub>		300			μs
Detection delay time					350	μs

### 2.6.4 LVD circuit characteristics

(Ta = -40 to +85°C, VPDR  $\leq$  EVDD = VDD  $\leq$  5.5 V, Vss = EVss = 0 V)

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection	Supply voltage level	VLVIO	Power supply rise time	3.98	4.06	4.14	V
voltage			Power supply fall time	3.90	3.98	4.06	V
		<b>V</b> LVI1	Power supply rise time	3.68	3.75	3.82	V
			Power supply fall time	3.60	3.67	3.74	V
		V <sub>LVI2</sub>	Power supply rise time	3.07	3.13	3.19	V
			Power supply fall time	3.00	3.06	3.12	٧
		<b>V</b> LVI3	Power supply rise time	2.96	3.02	3.08	٧
			Power supply fall time	2.90	2.96	3.02	V
		V <sub>LVI4</sub>	Power supply rise time	2.86	2.92	2.97	V
			Power supply fall time	2.80	2.86	2.91	V
		V <sub>LVI5</sub>	Power supply rise time	2.76	2.81	2.87	V
			Power supply fall time	2.70	2.75	2.81	V
		V <sub>LVI6</sub>	Power supply rise time	2.66	2.71	2.76	V
			Power supply fall time	2.60	2.65	2.70	V
		V <sub>LVI7</sub>	Power supply rise time	2.56	2.61	2.66	٧
			Power supply fall time	2.50	2.55	2.60	V
		V <sub>LVI8</sub>	Power supply rise time	2.45	2.50	2.55	V
			Power supply fall time	2.40	2.45	2.50	V
		V <sub>LVI9</sub>	Power supply rise time	2.05	2.09	2.13	V
			Power supply fall time	2.00	2.04	2.08	٧
		V <sub>LVI10</sub>	Power supply rise time	1.94	1.98	2.02	٧
			Power supply fall time	1.90	1.94	1.98	٧
		V <sub>LVI11</sub>	Power supply rise time	1.84	1.88	1.91	٧
			Power supply fall time	1.80	1.84	1.87	٧
		V <sub>LVI12</sub>	Power supply rise time	1.74	1.77	1.81	٧
			Power supply fall time	1.70	1.73	1.77	٧
		V <sub>LVI13</sub>	Power supply rise time	1.64	1.67	1.70	V
			Power supply fall time	1.60	1.63	1.66	V
Minimum pu	ulse width	t∟w		300			μS
Detection d	elay time	<b>t</b> LD				300	μS

**Remark**  $V_{LVI(n-1)} > V_{LVIn}$ : n = 1 to 13

### **LVD Detection Voltage of Interrupt & Reset Mode**

(Ta = -40 to +85°C, VPDR  $\leq$  EVDD = VDD  $\leq$  5.5 V, Vss = EVss = 0 V)

Parameter	Symbol	Co	nditions	MIN.	TYP.	MAX.	Unit
Interrupt and reset	V <sub>LVI13</sub>	VPOC0, VPOC1, VPOC2 = 0, 0,	0, falling reset voltage: 1.6 V	1.60	1.63	1.66	٧
mode	V <sub>LVI12</sub>	LVIS0, LVIS1 = 1,	Rising release reset voltage	1.74	1.77	1.81	V
		(+0.1 V)	Falling interrupt voltage	1.70	1.73	1.77	V
	V <sub>LVI11</sub>	LVIS0, LVIS1 = 0,	1 Rising release reset voltage	1.84	1.88	1.91	V
		(+0.2 V)	Falling interrupt voltage	1.80	1.84	1.87	V
	V <sub>LVI4</sub>	LVIS0, LVIS1 = 0,	Rising release reset voltage	2.86	2.92	2.97	V
		(+1.2 V)	Falling interrupt voltage	2.80	2.86	2.91	V
	V <sub>LVI11</sub>	$V_{POC0}$ , $V_{POC1}$ , $V_{POC2} = 0$ , 0,	1, falling reset voltage: 1.8 V	1.80	1.84	1.87	V
	V <sub>LVI10</sub>	LVIS0, LVIS1 = 1,	Rising release reset voltage	1.94	1.98	2.02	V
		(+0.1 V)	Falling interrupt voltage	1.90	1.94	1.98	V
	V <sub>LVI9</sub>	LVIS0, LVIS1 = 0,	1 Rising release reset voltage	2.05	2.09	2.13	V
		(+0.2 V)	Falling interrupt voltage	2.00	2.04	2.08	V
	V <sub>LVI2</sub>	LVIS0, LVIS1 = 0,	Rising release reset voltage	3.07	3.13	3.19	V
		(+1.2 V)	Falling interrupt voltage	3.00	3.06	3.12	٧
	V <sub>LVI8</sub>	VPOC0, VPOC1, VPOC2 = 0, 1,	0, falling reset voltage: 2.4 V	2.40	2.45	2.50	V
	V <sub>LVI7</sub>	LVIS0, LVIS1 = 1,	Rising release reset voltage	2.56	2.61	2.66	V
		(+0.1 V)	Falling interrupt voltage	2.50	2.55	2.60	V
	V <sub>LVI6</sub>	LVIS0, LVIS1 = 0,	1 Rising release reset voltage	2.66	2.71	2.76	V
		(+0.2 V)	Falling interrupt voltage	2.60	2.65	2.70	V
	V <sub>LVI1</sub>	LVIS0, LVIS1 = 0,	Rising release reset voltage	3.68	3.75	3.82	V
		(+1.2 V)	Falling interrupt voltage	3.60	3.67	3.74	V
	V <sub>LVI5</sub>	VPOC0, VPOC1, VPOC2 = 0, 1,	1, falling reset voltage: 2.7 V	2.70	2.75	2.81	V
	V <sub>LVI4</sub>	LVIS0, LVIS1 = 1,	Rising release reset voltage	2.86	2.92	2.97	V
		(+0.1 V)	Falling interrupt voltage	2.80	2.86	2.91	V
	V <sub>LVI3</sub>	LVIS0, LVIS1 = 0,	1 Rising release reset voltage	2.96	3.02	3.08	V
		(+0.2 V)	Falling interrupt voltage	2.90	2.96	3.02	V
	V <sub>L</sub> VI0 L	LVIS0, LVIS1 = 0,	Rising release reset voltage	3.98	4.06	4.14	٧
		(+1.2 V)	Falling interrupt voltage	3.90	3.98	4.06	٧

## **ELECTRICAL SPECIFICATIONS (TARGET)**

## Caution The pins mounted depend on the product. Refer to 1.3.1 32-pin products to 1.3.5 64-pin products.

## 2.6.5 Supply voltage rise time

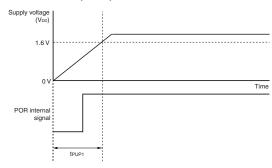
### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{ Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Maximum time to rise to 1.6 V (V <sub>DD</sub> (MIN.)) <sup>Note</sup> (V <sub>DD</sub> : 0 V $\rightarrow$ 1.6 V)	tpup1	When RESET input is not used			3.2	ms

**Note** Make sure to raise the power supply in a shorter time than this.

### **Supply Voltage Rise Time Timing**

### • When RESET pin input is not used



### 2.7 LCD Characteristics

### 2.7.1 Resistance division method

### (1) Static display mode

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{L4} \text{ (MIN.)} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	V <sub>L4</sub>		2.0		$V_{DD}$	٧
LCD output resistor <sup>Note</sup> (Common)	Rodc	$Io = \pm 5 \mu A$			40	kΩ
LCD output resistor <sup>Note</sup> (Segment)	Rocs	$Io = \pm 1 \mu A$			200	kΩ

### (2) 1/2 bias method, 1/4 bias method

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{L4} \text{ (MIN.)} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	V <sub>L4</sub>		2.7		$V_{DD}$	٧
LCD output resistor <sup>Note</sup> (Common)	Rodc	$lo = \pm 5 \mu A$			40	kΩ
LCD output resistor <sup>Note</sup> (Segment)	Rocs	$lo = \pm 1 \mu A$			200	kΩ

### (3) 1/3 bias method

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{L4} \text{ (MIN.)} \le V_{DD} \le 5.5 \text{ V. Vss} = 0 \text{ V})$ 

(17 - 40 10 100 0, 124 (1111	14.) = 400	<u> </u>				
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	V <sub>L4</sub>		2.5		V <sub>DD</sub> <sup>Note2</sup>	٧
LCD output resistor <sup>Note1</sup> (Common)	Rodc	$lo = \pm 5 \mu A$			40	kΩ
LCD output resistor <sup>Note1</sup> (Segment)	Rocs	$lo = \pm 1 \mu A$			200	kΩ

- Notes 1. The output resistor is a resistor connected between one of the VL1, VL2, VL3, VL4 and Vss pins, and either of the SEG and COM pins.
  - 2. 5.5 V (MAX) when driving a memory-type liquid crystal (the MLCDEN bit of the MLCD register = 1).

### 2.7.2 Internal voltage boosting method

### (1) 1/3 bias method

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{ Vss} = 0 \text{ V})$ 

Parameter	Symbol	I .		MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	V <sub>L1</sub>	C1 to C4 <sup>Note 1</sup>	VLCD = 02H	T.B.D.	0.90	T.B.D.	V
		$= 0.47 \ \mu F^{\text{Note 2}}$	VLCD = 03H	T.B.D.	0.95	T.B.D.	V
			VLCD = 04H	T.B.D.	1.00	T.B.D.	V
			VLCD = 05H	T.B.D.	1.05	T.B.D.	V
			VLCD = 06H	T.B.D.	1.10	T.B.D.	V
			VLCD = 07H	T.B.D.	1.15	T.B.D.	V
			VLCD = 08H	T.B.D.	1.20	T.B.D.	V
			VLCD = 09H	T.B.D.	1.25	T.B.D.	V
			VLCD = 0AH	T.B.D.	1.30	T.B.D.	V
			VLCD = 0BH	T.B.D.	1.35	T.B.D.	V
			VLCD = 0CH	T.B.D.	1.40	T.B.D.	V
			VLCD = 0DH	T.B.D.	1.45	T.B.D.	V
			VLCD = 0EH	T.B.D.	1.50	T.B.D.	V
			VLCD = 0FH	T.B.D.	1.55	T.B.D.	V
			VLCD = 10H	T.B.D.	1.60	T.B.D.	V
			VLCD = 11H	T.B.D.	1.65	T.B.D.	V
			VLCD = 12H	T.B.D.	1.70	T.B.D.	V
			VLCD = 13H	T.B.D.	1.75	T.B.D.	V
Doubler output voltage	V <sub>L2</sub>	C1 to C4 <sup>Note 1</sup> =	0.47 <i>μ</i> F	2 V <sub>L1</sub> -0.1	2 V <sub>L1</sub>	2 V <sub>L1</sub>	V
Tripler output voltage	<b>V</b> L3	C1 to C4 <sup>Note 1</sup> =	0.47 <i>μ</i> F	3 V <sub>L1</sub> -0.15	3 V <sub>L1</sub>	3 V <sub>L1</sub>	V
Reference voltage setup time Note 2	tvwait1			5			ms
Voltage boost wait time <sup>Note 3</sup>	tvwait2	C1 to C4 <sup>Note 1</sup> =	0.47 <i>μ</i> F	500			ms
		V <sub>DD</sub> > V <sub>L4</sub>		T.B.D.			ms
LCD output resistor <sup>Note 4</sup> (Common)	Rodc	Io = ±5 μA				40	kΩ
LCD output resistorNote 4 (Segment)	Rocs	Io = ±1 μA				200	kΩ

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

- C1: A capacitor connected between CAPH and CAPL
- C2: A capacitor connected between V<sub>L1</sub> and GND
- C3: A capacitor connected between V<sub>L2</sub> and GND
- C4: A capacitor connected between VL3 and GND
- $C1 = C2 = C3 = C4 = 0.47 pF \pm 30 \%$
- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected [by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B] if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).
- **4.** The output resistor is a resistor connected between one of the V<sub>L1</sub>, V<sub>L2</sub>, V<sub>L3</sub>, V<sub>L4</sub> and V<sub>SS</sub> pins, and either of the SEG and COM pins.



### (2) 1/4 bias method

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol	Cor	nditions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	V <sub>L1</sub>	C1 to C5 <sup>Note 1</sup>	VLCD = 02H	T.B.D.	0.90	T.B.D.	V
		$= 0.47 \ \mu F^{\text{Note 2}}$	VLCD = 03H	T.B.D.	0.95	T.B.D.	V
			VLCD = 04H	T.B.D.	1.00	T.B.D.	V
			VLCD = 05H	T.B.D.	1.05	T.B.D.	V
			VLCD = 06H	T.B.D.	1.10	T.B.D.	V
			VLCD = 07H	T.B.D.	1.15	T.B.D.	V
			VLCD = 08H	T.B.D.	1.20	T.B.D.	V
			VLCD = 09H	T.B.D.	1.25	T.B.D.	V
			VLCD = 0AH	T.B.D.	1.30	T.B.D.	V
			VLCD = 0BH	T.B.D.	1.35	T.B.D.	V
			VLCD = 0CH	T.B.D.	1.40	T.B.D.	V
			VLCD = 0DH	T.B.D.	1.45	T.B.D.	V
			VLCD = 0EH	T.B.D.	1.50	T.B.D.	V
			VLCD = 0FH	T.B.D.	1.55	T.B.D.	V
			VLCD = 10H	T.B.D.	1.60	T.B.D.	V
			VLCD = 11H	T.B.D.	1.65	T.B.D.	V
			VLCD = 12H	T.B.D.	1.70	T.B.D.	V
			VLCD = 13H	T.B.D.	1.75	T.B.D.	V
Doubler output voltage	V <sub>L2</sub>	C1 to C5 <sup>Note 1</sup> =	0.47 <i>μ</i> F	2 V <sub>L1</sub> -0.08	2 V <sub>L1</sub>	2 V <sub>L1</sub>	V
Tripler output voltage	<b>V</b> L3	C1 to C5 <sup>Note 1</sup> =	0.47 <i>μ</i> F	3 V <sub>L1</sub> -0.12	3 V <sub>L1</sub>	3 V <sub>L1</sub>	V
Quadruply output voltage	V <sub>L4</sub>	C1 to C5 <sup>Note 1</sup> =	0.47 <i>μ</i> F	4 V <sub>L1</sub> –0.16	4 V <sub>L1</sub>	4 V <sub>L1</sub>	V
Reference voltage setup time Note 2	tvwait1			5			ms
Voltage boost wait time <sup>Note 3</sup>	tvwait2	C1 to $C5^{\text{Note 1}} = 0.47 \ \mu\text{F}$		500			ms
		V <sub>DD</sub> > V <sub>L4</sub>		T.B.D.			ms
LCD output resistor <sup>Note 4</sup> (Common)	Rodc	Io = ±5 μA				40	kΩ
LCD output resistorNote 4 (Segment)	Rocs	Io = ±1 μA				200	kΩ

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

- C1: A capacitor connected between CAPH and CAPL
- C2: A capacitor connected between V<sub>L1</sub> and GND
- C3: A capacitor connected between VL2 and GND
- C4: A capacitor connected between VL3 and GND
- C5: A capacitor connected between  $V_{\mathsf{L4}}$  and GND
- $C1 = C2 = C3 = C4 = C5 = 0.47 \text{ pF} \pm 30 \%$
- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected [by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B] if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).
- **4.** The output resistor is a resistor connected between one of the V<sub>L1</sub>, V<sub>L2</sub>, V<sub>L3</sub>, V<sub>L4</sub> and V<sub>SS</sub> pins, and either of the SEG and COM pins.



### **ELECTRICAL SPECIFICATIONS (TARGET)**

### Caution The pins mounted depend on the product. Refer to 1.3.1 32-pin products to 1.3.5 64-pin products.

#### 2.7.3 Capacitor split method

### (1) 1/3 bias method

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.2 \text{ V} \le \text{V}_{DD} = \text{EV}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
V <sub>L4</sub> voltage	V <sub>L4</sub>	C1 to C4 = 0.47 $\mu$ F <sup>Note 3</sup>		V <sub>DD</sub>		V
V <sub>L2</sub> voltage	V <sub>L2</sub>	C1 to C4 = 0.47 $\mu$ F <sup>Note 3</sup>	2/3 V <sub>L4</sub> -0.1	2/3 V <sub>L4</sub>	2/3 V <sub>L4</sub> +0.1	V
V <sub>L1</sub> voltage	V <sub>L1</sub>	C1 to C4 = 0.47 $\mu$ F <sup>Note 3</sup>	1/3 V <sub>L4</sub> -0.1	1/3 V <sub>L4</sub>	1/3 V <sub>L4</sub> +0.1	V
Capacitor split wait timeNote 1	tvwait		100			ms
LCD output resistor Note 2 (Common)	Rodc	$lo = \pm 5 \mu A$			40	kΩ
LCD output resistor Note 2 (Segment)	Rocs	$lo = \pm 1 \mu A$			200	kΩ

- Notes 1. This is the wait time from when voltage bucking is started (VLCON = 1) until display is enabled (LCDON = 1).
  - 2. The output resistor is a resistor connected between one of the VL1, VL2, VL3, VL4 and Vss pins, and either of the SEG and COM pins.
  - 3. This is a capacitor that is connected between voltage pins used to drive the LCD.
    - C1: A capacitor connected between CAPH and CAPL
    - C2: A capacitor connected between V<sub>L1</sub> and GND
    - C3: A capacitor connected between VL2 and GND
    - C4: A capacitor connected between VL4 and GND
    - $C1 = C2 = C3 = C4 = 0.47 \text{ pF} \pm 30 \%$

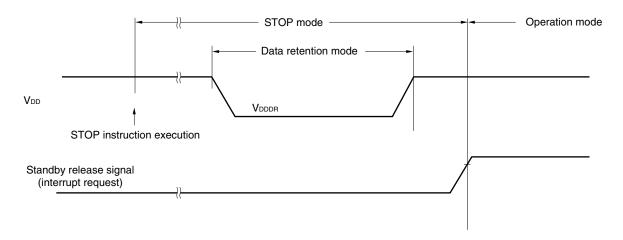
# products.

### 2.8 Data Memory STOP Mode Low Supply Voltage Data Retention Characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.47 <sup>Note</sup>		5.5	V

Note The value depends on the POR detection voltage. When the voltage drops, the data is retained before a POR reset is effected, but data is not retained when a POR reset is effected.



### Flash Memory Programming Characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}. 1.8 \text{ V} < \text{FV}_{DD} = \text{V}_{DD} < 5.5 \text{ V}. \text{Vss} = \text{FV}_{SS} = 0 \text{ V})$ 

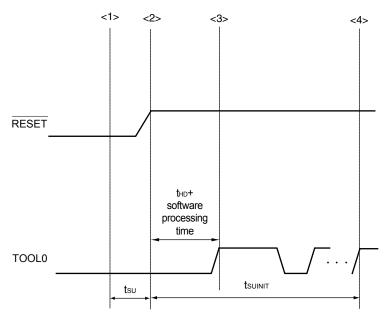
1A = -40 to +65 C, 1.6 V \( \) EVDD = VDD \( \) 5.5 V, VSS = EVSS = 0 V)							
Parameter	Symbol	Condi	Conditions			MAX.	Unit
CPU/peripheral hardware clock frequency	fclk	$1.8~V \leq V_{DD} \leq 5.5~V$		1		24	MHz
Number of code flash rewrites	Cerwr	1 erase + 1 write after the erase is regarded as 1 rewrite.	Retained for 20 years (Self/serial programming) Note	1,000			Times
Number of data flash rewrites		The retaining years are until next rewrite after the rewrite.	Retained for 1 years (Self/serial programming) Note		1,000,000		
			Retained for 5 years (Self/serial programming) Note	100,000			

Note When using flash memory programmer and Renesas Electronics self programming library

Remark When updating data multiple times, use the flash memory as one for updating data.

### Timing Specs for Switching Modes

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
How long from when a pin reset ends until the initial communication settings are specified	tsuinit	POR and LVD reset must end before the pin reset ends.			100	ms
How long from when the TOOL0 pin is placed at the low level until a pin reset ends	tsu	POR and LVD reset must end before the pin reset ends.	10			μs
How long the TOOL0 pin must be kept at the low level after a reset ends	tно	POR and LVD reset must end before the pin reset ends.	1			ms



- <1> The low level is input to the TOOL0 pin.
- The pins reset ends (POR and LVD reset must end before the pin reset ends.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.

Remark tsuinit: The segment shows that it is necessary to finish specifying the initial communication settings within 100 ms from when the external and internal resets end.

tsu: How long from when the TOOL0 pin is placed at the low level until a pin reset ends

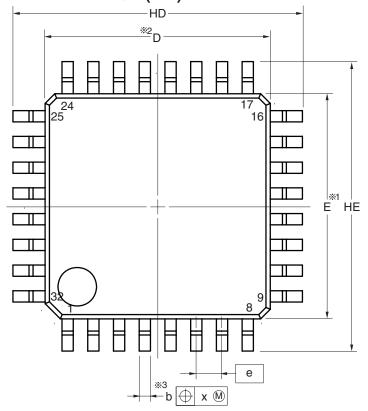
How long to keep the TOOL0 pin at the low level from when the external and internal resets end thd:

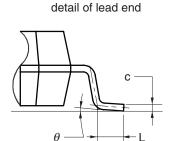
### 3. PACKAGE DRAWINGS

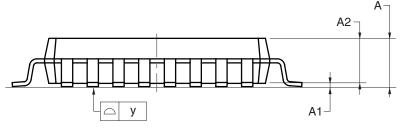
### 3.1 32-pin products

R5F10RB8AFP, R5F10RBAAFP, R5F10RBCAFP

## 32-PIN PLASTIC LQFP(7x7)







### (UNIT:mm)

	(3111111111)
ITEM	DIMENSIONS
D	7.00±0.10
E	7.00±0.10
HD	9.00±0.20
HE	9.00±0.20
Α	1.70 MAX.
A1	0.10±0.10
A2	1.40
b	0.37±0.05
С	0.145±0.055
L	0.50±0.20
θ	0° to 8°
е	0.80
Х	0.20
У	0.10
	P32GA-80-GBT

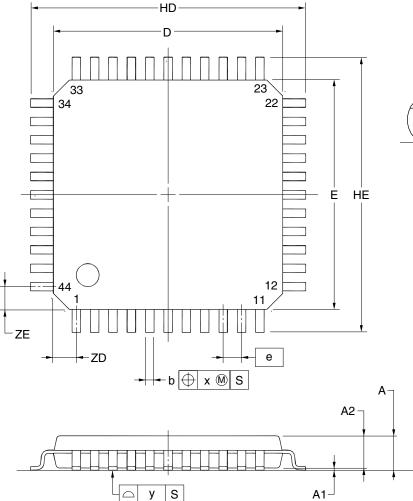
### NOTE

- 1.Dimensions "%1" and "%2" do not include mold flash.
- 2.Dimension "%3" does not include trim offset.

## 3.2 44-pin products

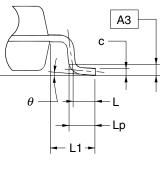
R5F10RF8AFP, R5F10RFAAFP, R5F10RFCAFP

# 44-PIN PLASTIC LQFP(10x10)



Specifications in this document are tentative and subject to change.

detail of lead end



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(UNIT:mm)

ITEM	DIMENSIONS
D	10.00±0.20
E	10.00±0.20
HD	12.00±0.20
HE	12.00±0.20
Α	1.60 MAX.
A1	0.10±0.05
A2	1.40±0.05
A3	0.25
b	$0.37^{+0.08}_{-0.07}$
С	$0.145^{+0.055}_{-0.045}$
L	0.50
Lp	0.60±0.15
L1	1.00±0.20
θ	3°+5° -3°
е	0.80
х	0.20
у	0.10
ZD	1.00
ZE	1.00
	P44GB-80-UES-1

### NOTE

Each lead centerline is located within 0.20 mm of its true position at maximum material condition.

АЗ

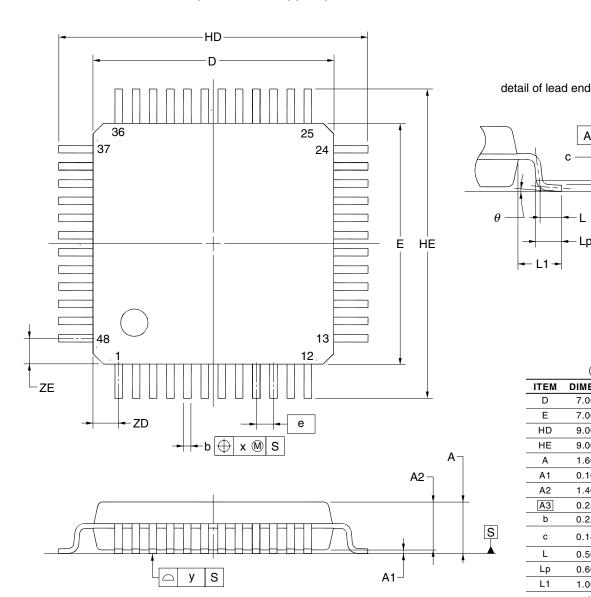
Lp

С

### 3.3 48-pin products

R5F10RG8AFB, R5F10RGAAFB, R5F10RGCAFB

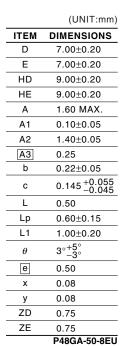
## 48-PIN PLASTIC LQFP (FINE PITCH)(7x7)



Specifications in this document are tentative and subject to change.

## NOTE

Each lead centerline is located within 0.08 mm of its true position at maximum material condition.



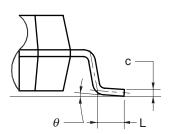
RENESAS

## 3.4 52-pin products

R5F10RJ8AFA, R5F10RJAAFA, R5F10RJCAFA

# 52-PIN PLASTIC LQFP (10x10) 26 Ē HE $\blacksquare$ е ⊕ x M Α2

detail of lead end



A1

### NOTE

- 1.Dimensions "%1" and "%2" do not include mold flash.
- 2.Dimension "%3" does not include trim offset.

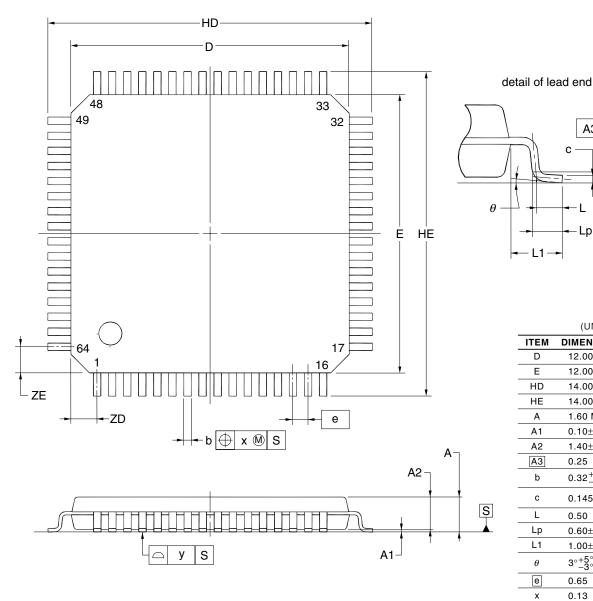
(UNIT:mm) DIMENSIONS ITEM 10.00±0.10 D Е 10.00±0.10 HD 12.00±0.20 ΗE 12.00±0.20 1.70 MAX. 0.10±0.05 Α1 Α2 1.40 b 0.32±0.05 С  $0.145 \pm 0.055$ L 0.50±0.15  $0^{\circ}$  to  $8^{\circ}$ е 0.65 0.13 0.10 у

P52GB-65-GBS

### 3.5 64-pin products

R5F10RLAAFA, R5F10RLCAFA

## 64-PIN PLASTIC LQFP(12x12)



Specifications in this document are tentative and subject to change.

NOTE
Each lead centerline is located within 0.13 mm of
its true position at maximum material condition.

(UNIT:mm) ITEM DIMENSIONS D 12.00±0.20 Ε 12.00±0.20 HD 14.00±0.20 ΗE 14.00±0.20 1.60 MAX. Α1 0.10±0.05 1.40±0.05 Α2 А3 0.25  $0.32^{+0.08}_{-0.07}$  $0.145^{\,+0.055}_{\,-0.045}$ 0.50  $0.60\pm0.15$ L1 1.00±0.20  $\theta$ 3°+5° е 0.65 0.13 Х 0.10 ZD 1.125 ZΕ 1.125 P64GK-65-UET-1

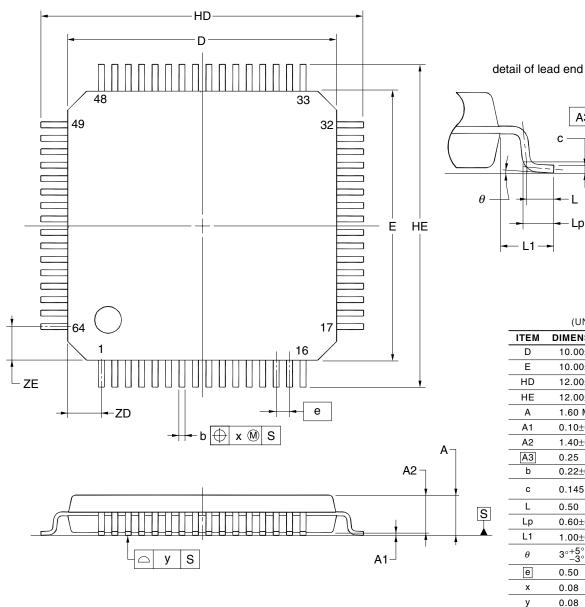
АЗ

– Lp

АЗ

– Lp

# 64-PIN PLASTIC LQFP(FINE PITCH)(10x10)



Specifications in this document are tentative and subject to change.

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1.4	v		ᆮ

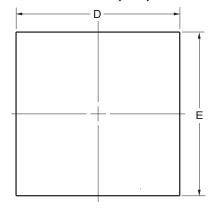
Each lead centerline is located within 0.08 mm of its true position at maximum material condition.

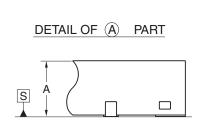
	(UNIT:mm)
ITEM	DIMENSIONS
D	10.00±0.20
E	10.00±0.20
HD	12.00±0.20
HE	12.00±0.20
Α	1.60 MAX.
A1	0.10±0.05
A2	1.40±0.05
A3	0.25
b	0.22±0.05
С	$0.145{}^{+0.055}_{-0.045}$
L	0.50
Lp	0.60±0.15
L1	1.00±0.20
θ	3°+5° -3°
е	0.50
х	0.08
У	0.08
ZD	1.25
ZE	1.25
	P64GB-50-UEU-1

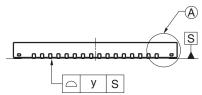
Specifications in this document are tentative and subject to change.

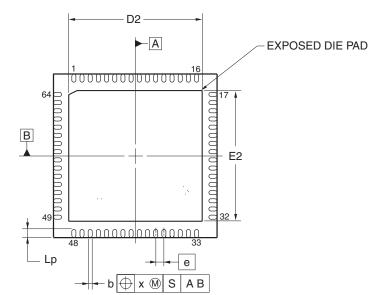
R5F10RLAANB, R5F10RLCANB

## 64-PIN PLASTIC WQFN(8x8)









	(UNIT:mm)
ITEM	DIMENSIONS
D	8.00±0.05
E	8.00±0.05
Α	$0.75 \pm 0.05$
b	0.20±0.05
е	0.40
Lp	$0.40\pm0.10$
х	0.05
у	0.05
	P64K8-40-9B5

ITEM		D2		E2			
		MIN	NOM	MAX	MIN	NOM	MAX
EXPOSED DIE PAD VARIATIONS	Α	6.45	6.50	6.55	6.45	6.50	6.55

**Revision History** 

# RL78/L12 Data Sheet

			Description			
Rev.	Date	Page	Summary			
0.01	Feb 20, 2012	-	First Edition issued			

### NOTES FOR CMOS DEVICES

- (1) VOLTAGE APPLICATION WAVEFORM AT INPUT PIN: Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between VIL (MAX) and VIH (MIN) due to noise, etc., the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between VIL (MAX) and VIH (MIN).
- (2) HANDLING OF UNUSED INPUT PINS: Unconnected CMOS device inputs can be cause of malfunction. If an input pin is unconnected, it is possible that an internal input level may be generated due to noise, etc., causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND via a resistor if there is a possibility that it will be an output pin. All handling related to unused pins must be judged separately for each device and according to related specifications governing the device.
- (3) PRECAUTION AGAINST ESD: A strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it when it has occurred. Environmental control must be adequate. When it is dry, a humidifier should be used. It is recommended to avoid using insulators that easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors should be grounded. The operator should be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with mounted semiconductor devices.
- (4) STATUS BEFORE INITIALIZATION: Power-on does not necessarily define the initial status of a MOS device. Immediately after the power source is turned ON, devices with reset functions have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. A device is not initialized until the reset signal is received. A reset operation must be executed immediately after power-on for devices with reset functions.
- (5) POWER ON/OFF SEQUENCE: In the case of a device that uses different power supplies for the internal operation and external interface, as a rule, switch on the external power supply after switching on the internal power supply. When switching the power supply off, as a rule, switch off the external power supply and then the internal power supply. Use of the reverse power on/off sequences may result in the application of an overvoltage to the internal elements of the device, causing malfunction and degradation of internal elements due to the passage of an abnormal current. The correct power on/off sequence must be judged separately for each device and according to related specifications governing the device.
- (6) INPUT OF SIGNAL DURING POWER OFF STATE: Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Input of signals during the power off state must be judged separately for each device and according to related specifications governing the device.

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